



The dRICH photosensors: SiPM studies

Giornate Nazionali EIC_NET 2024
Bologna 27 – 28 Jun 2024

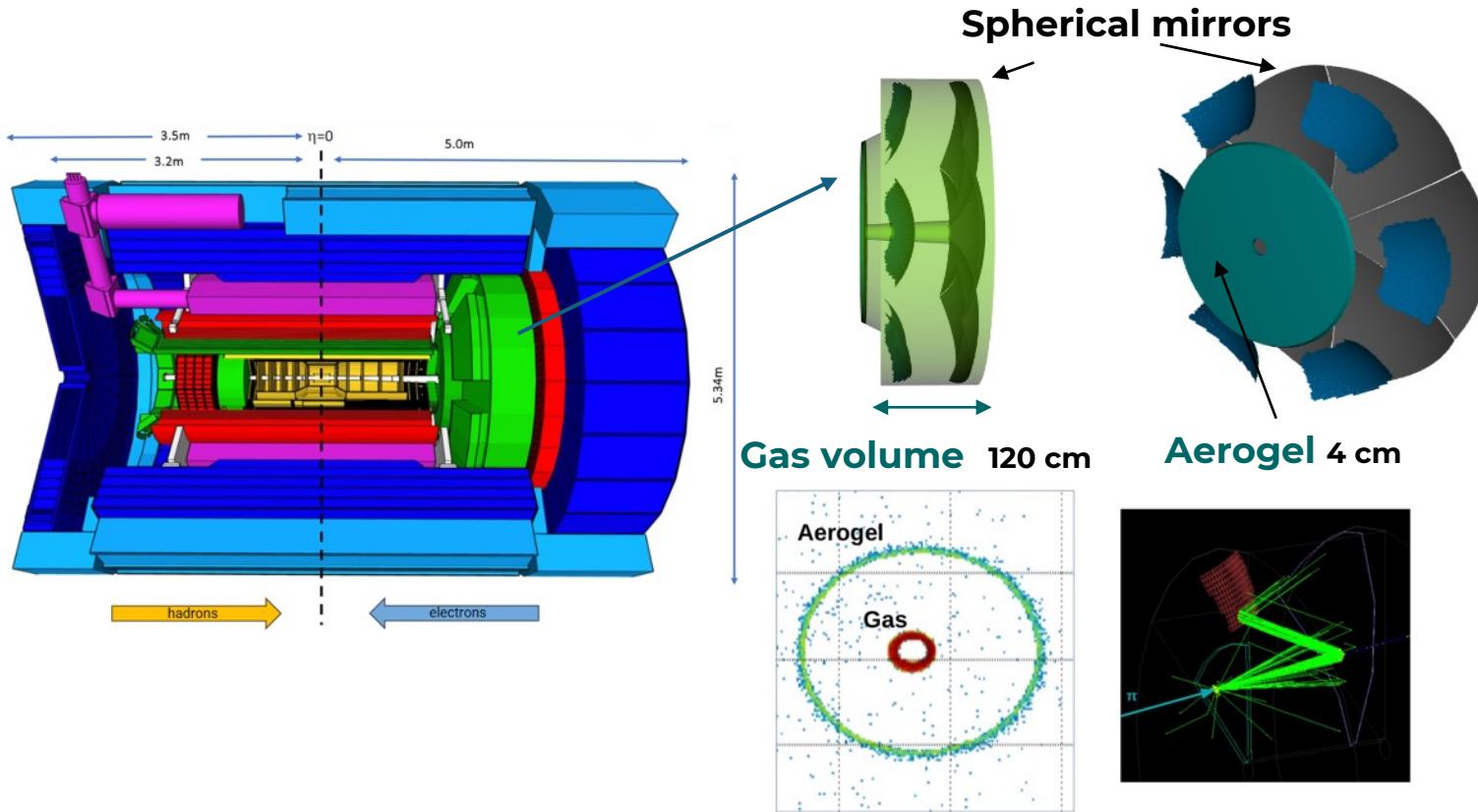
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Outline

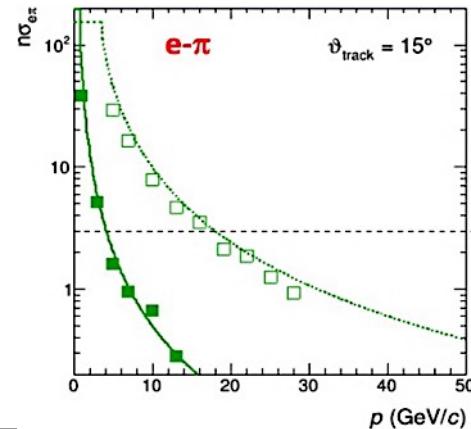
- *Introduction*
- *Current annealing update*
- *Neutron irradiation*
- *Proton energy scan*
- *Next irradiation campaigns*
- *New laser setup*
- *Windows damage studies*
- *New Hamamatsu prototypes*
- *Slew rate vs ToT*
- *Update radiation simulations and aging model*

Introduction: the dual-radiator (dRICH) for forward PID

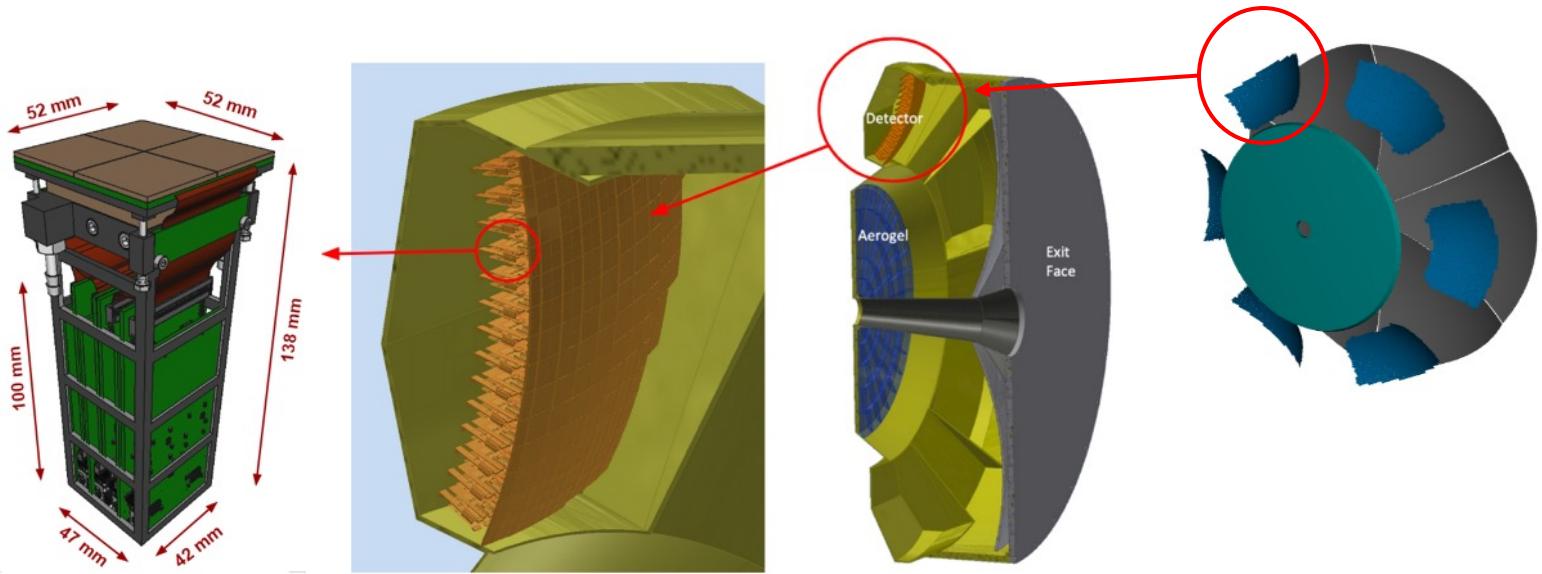
Compact and cost-effective solution for broad momentum (3-50 GeV/c) coverage at forward rapidity π/K 3σ separation at 50 GeV/c



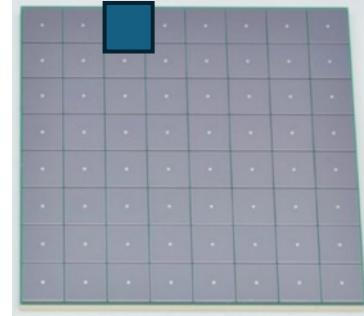
RADIATORS: aerogel ($n \sim 1.02$) and C_2F_6 ($n \sim 1.0008$)
MIRRORS: 6 open sectors of large outward-reflecting
Photosensors: $3 \times 3 \text{ mm}^2$ pixels 0.5 m^2 per sector in 1 T magnetic field and radioactive environnement for low light level detection.



Introduction: the photosensors



$3 \times 3 \text{ mm}^2$



SiPM is the best photosensor candidate:

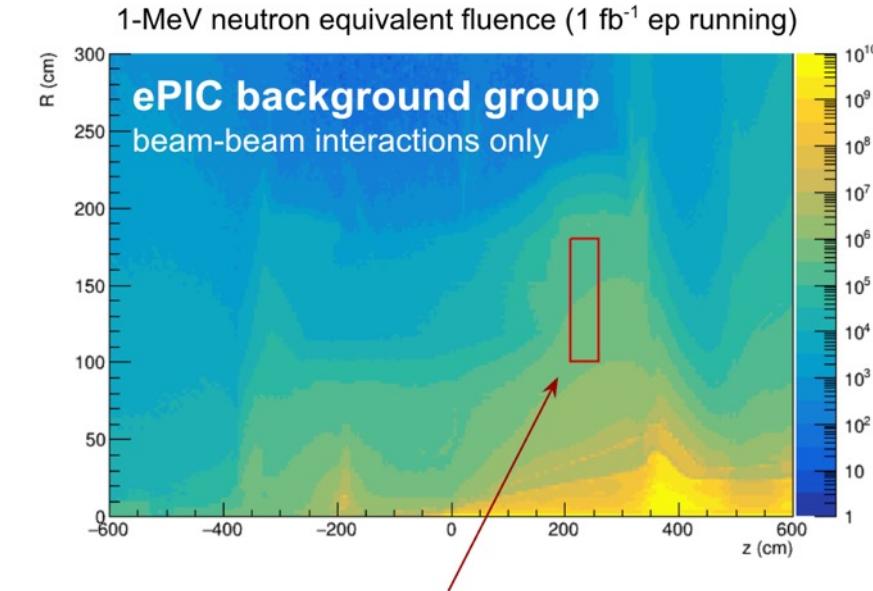
Single Photon sensitivity ~ 10 phs per Cherenkov event

Good timing performance < 100 ps

Cheap and **insensitive** to magnetic fields

BUT

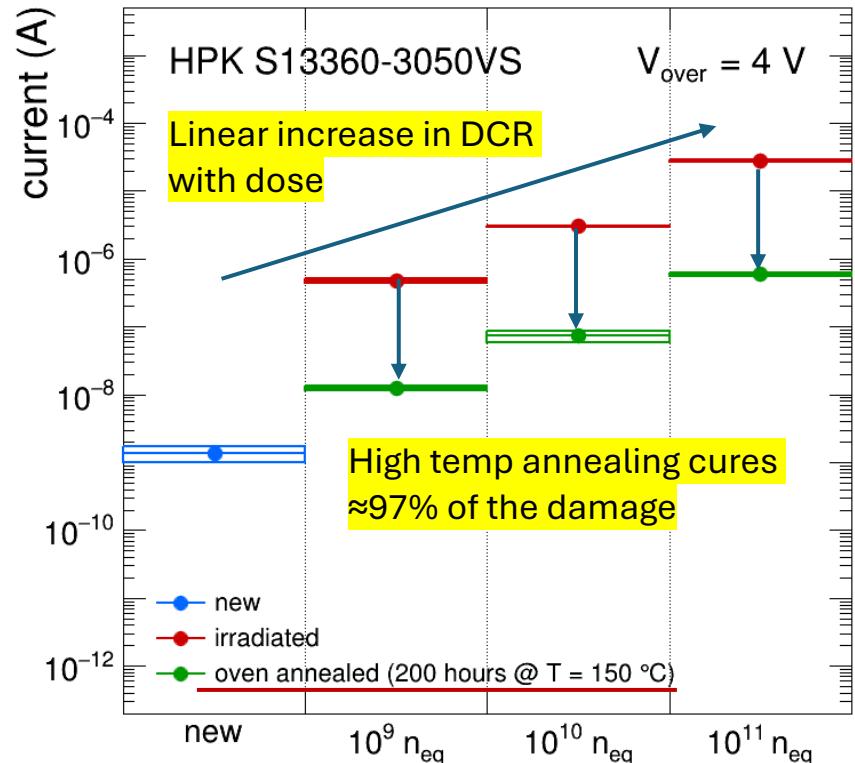
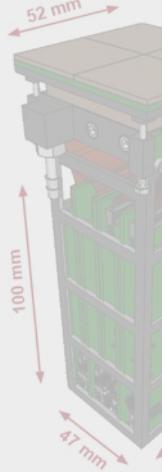
High DCR @RT and **high radiation sensitivity**



Location of photosensors
 $\text{Max fluence} \approx 2.25 \times 10^7 \text{ n}_{\text{eq}} / \text{cm}^2 / \text{fb}^{-1}$
 $\text{Max fluence (SFx2)} \approx 4.5 \times 10^7 \text{ n}_{\text{eq}} / \text{cm}^2 / \text{fb}^{-1}$

Values changed in the last simulations!

Introduction: the photosensors



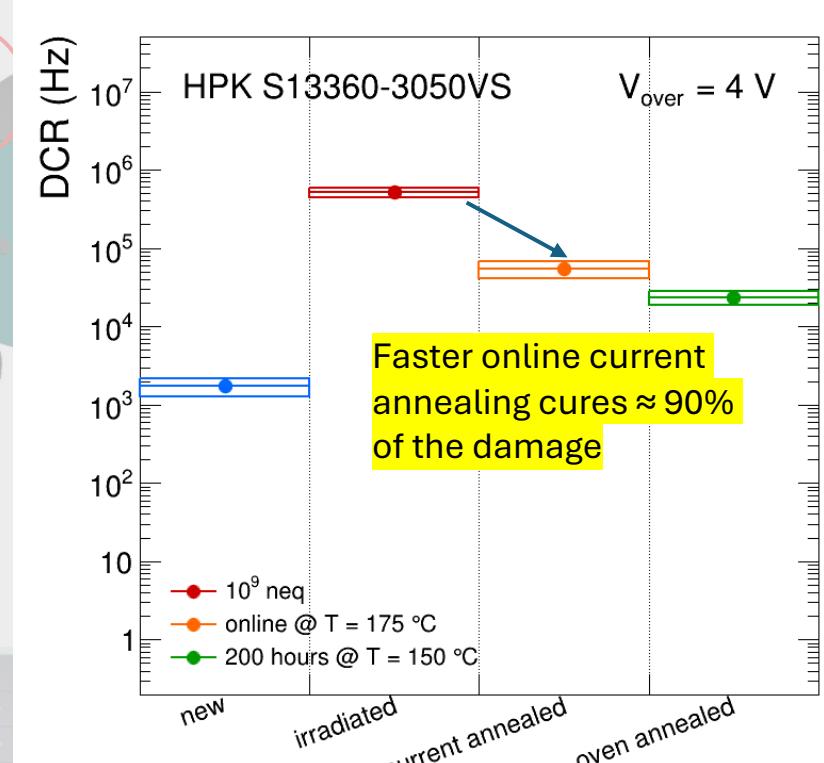
SiPM is the Single Photon Sensor

Good timing performance $< 100 \text{ ps}$

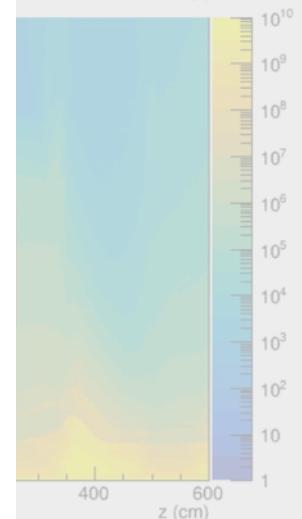
Cheap and insensitive to magnetic fields

BUT

High DCR @RT and high radiation sensitivity



fb^{-1} ep running)



sensors

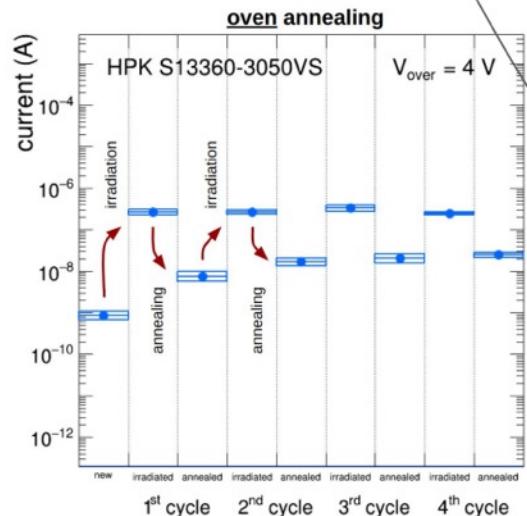
$$2.25 \cdot 10^7 \text{ } n_{eq} / \text{cm}^2 / \text{fb}^{-1}$$

Total fluence (100 fb^{-1}):

$$\approx 4.5 \cdot 10^{10} \text{ } n_{eq} / \text{cm}^2$$

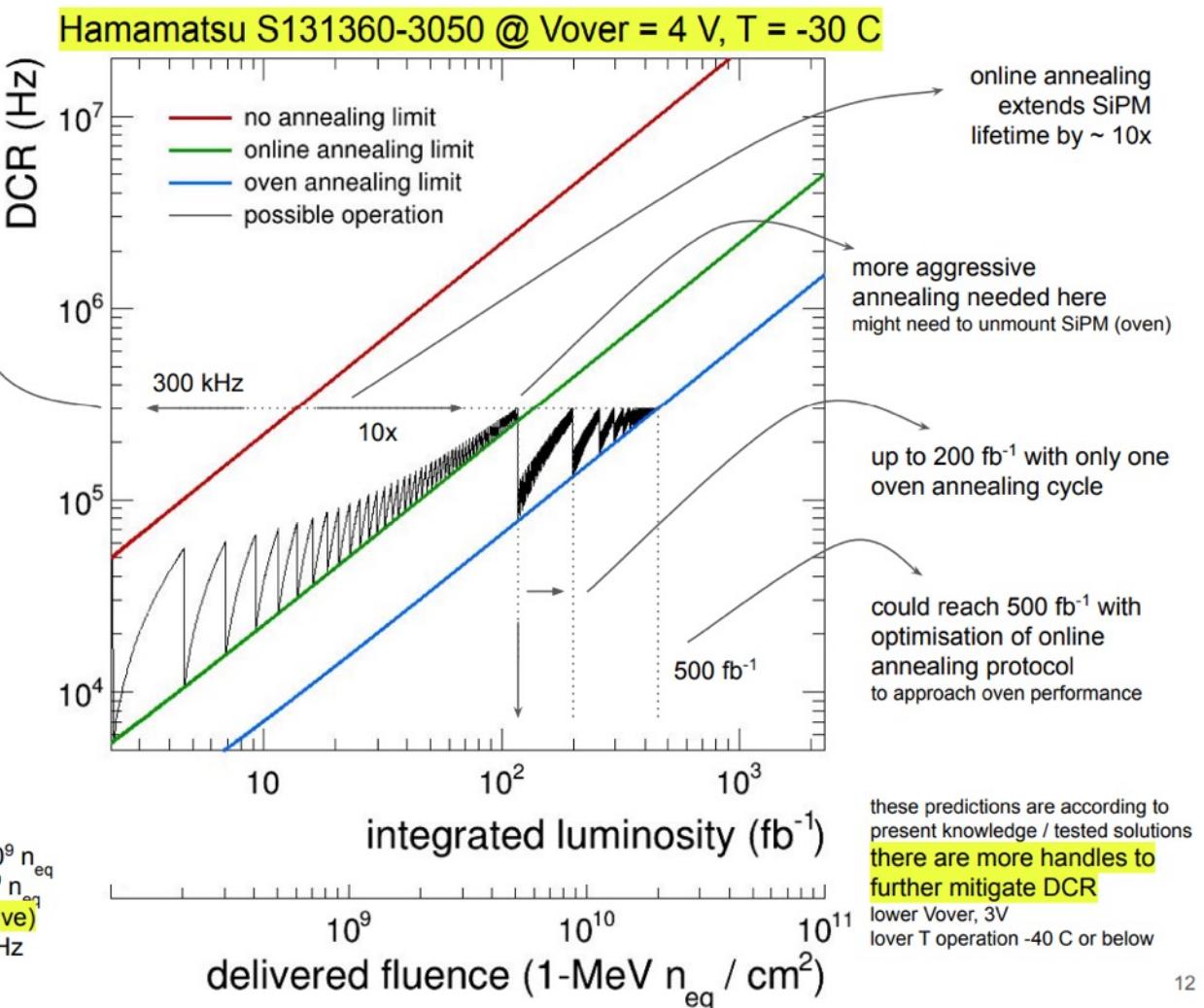
Ageing model

max acceptable DCR for Physics performance
 ~ 10 noise hits / sector within 500 ps



model input from R&D measurements

- DCR increase: $500 \text{ kHz}/10^9 n_{\text{eq}}$
 - residual DCR (online annealing): $50 \text{ kHz}/10^9 n_{\text{eq}}$
 - residual DCR (oven annealing): $15 \text{ kHz}/10^9 n_{\text{eq}}$
- neutron fluence from background group (conservative)
- $7 \cdot 10^9 \text{ 1-MeV } n_{\text{eq}}/\text{cm}^2$ for 6 months at 500 kHz
 - corresponds to $4.5 \cdot 10^7 n_{\text{eq}}/\text{fb}^{-1}$

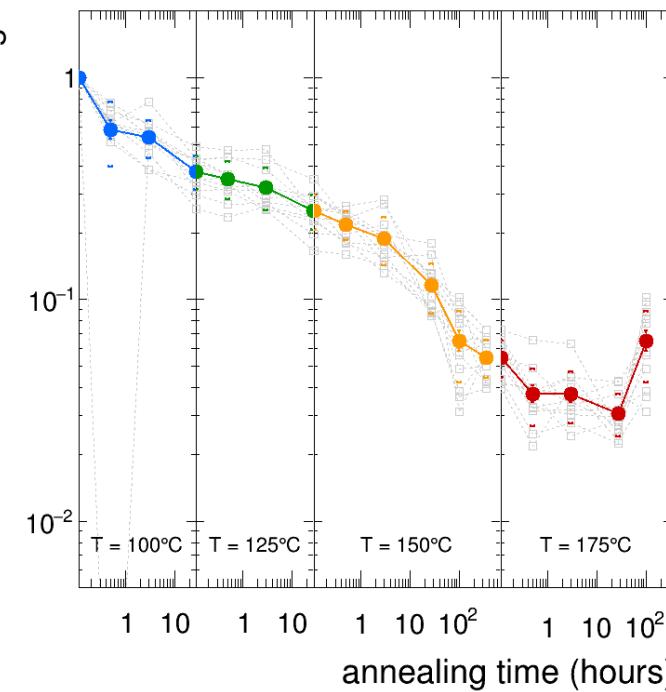


Update on current annealing

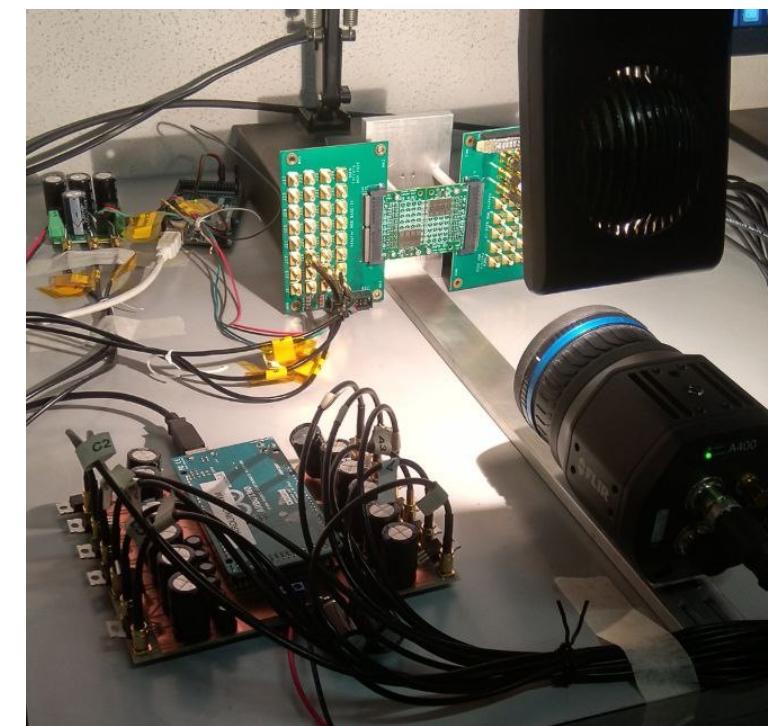
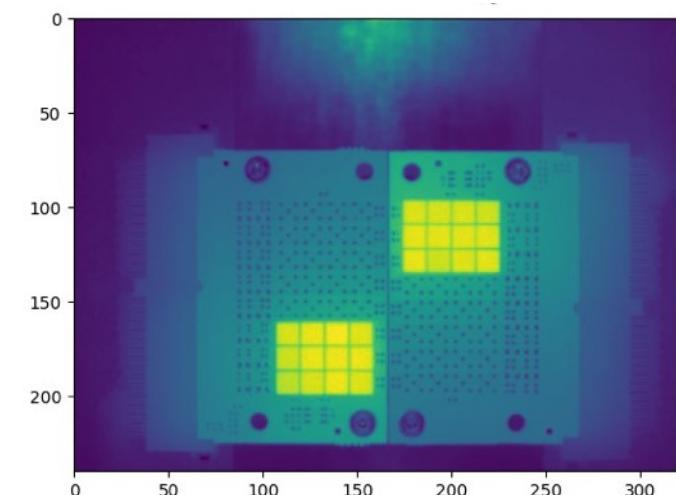
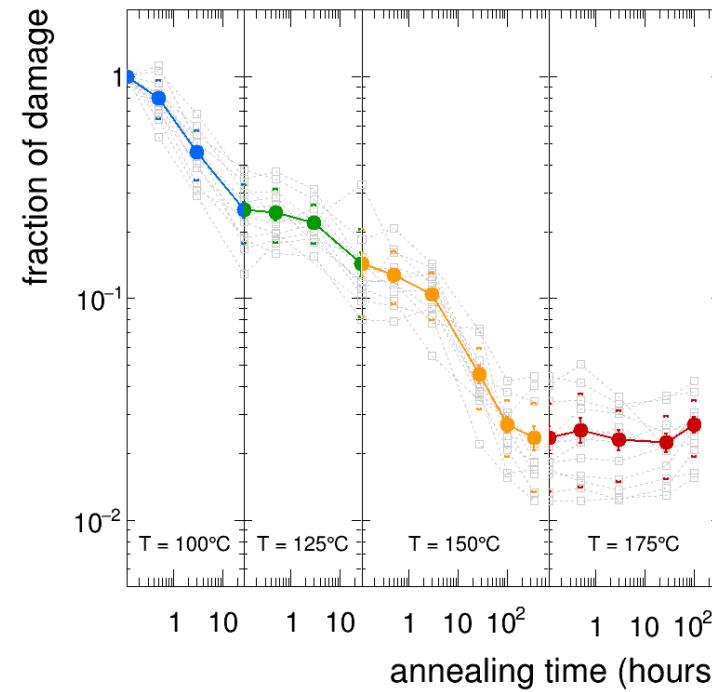
New **automated system** for **reverse** and **forward bias** allowed to test a **large number** of **irradiated** sensors at increasing **temperatures** and **time** (following procedures in literature).

$$\text{Fraction of damage} = \text{DCR}_{\text{ann}} / \text{DCR}_{\text{irr}}$$

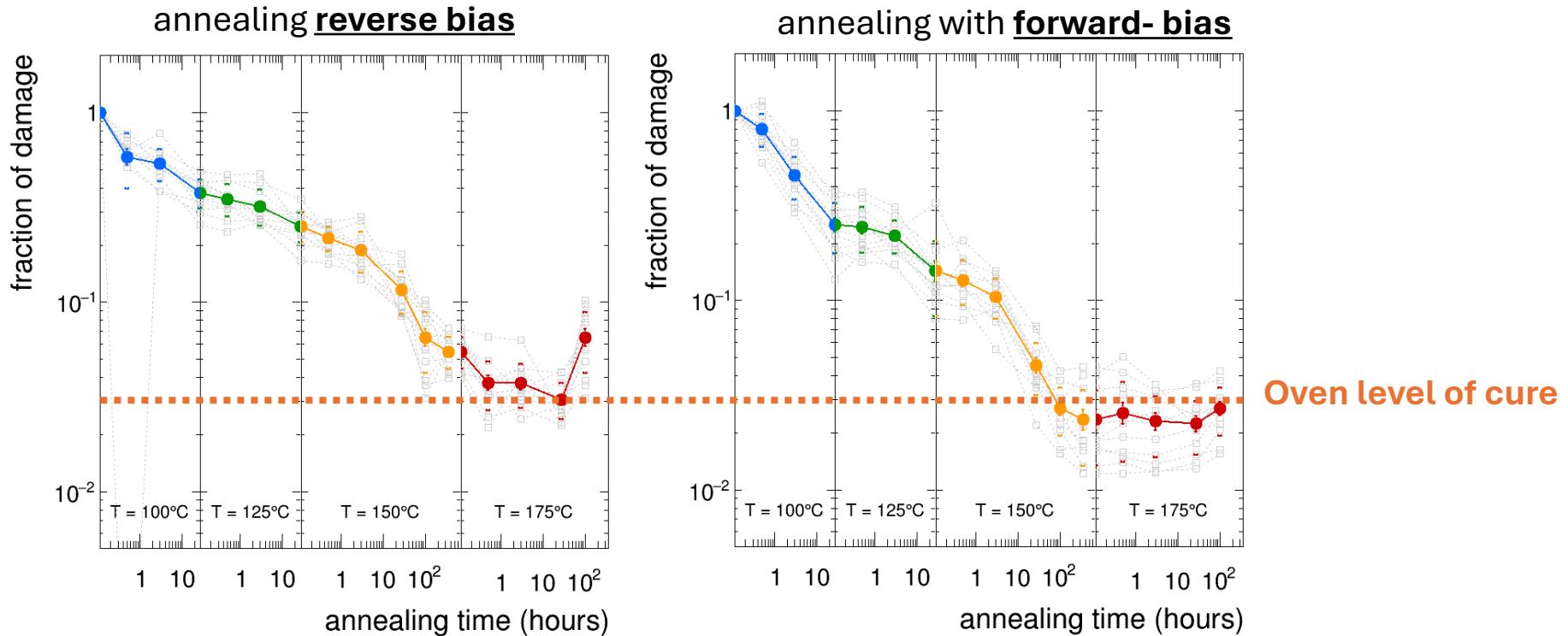
annealing reverse bias



annealing with forward- bias



Update on current annealing

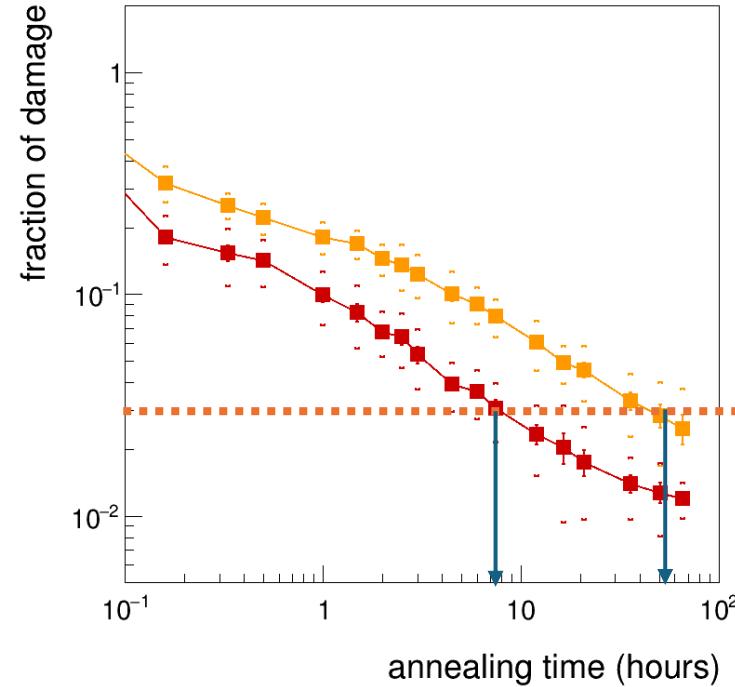
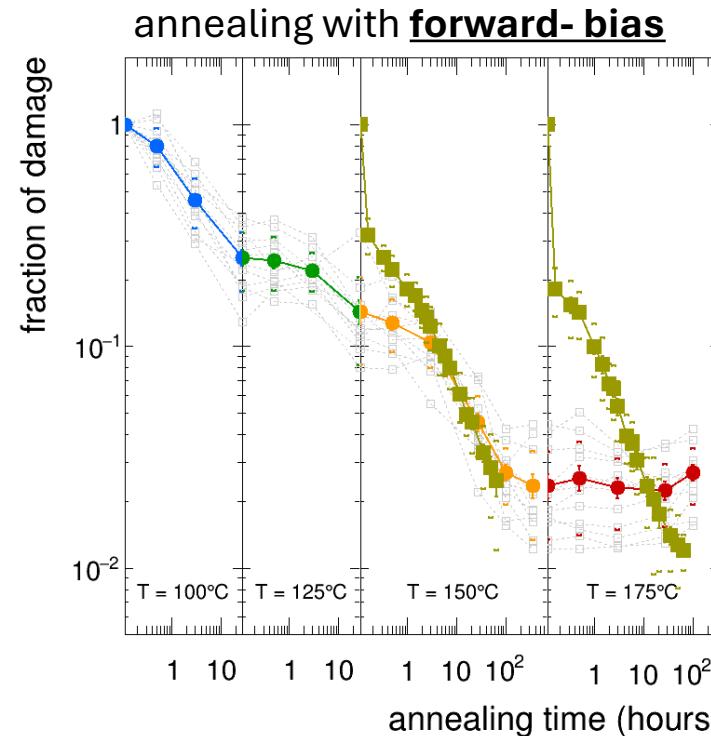


Forward bias is more effective

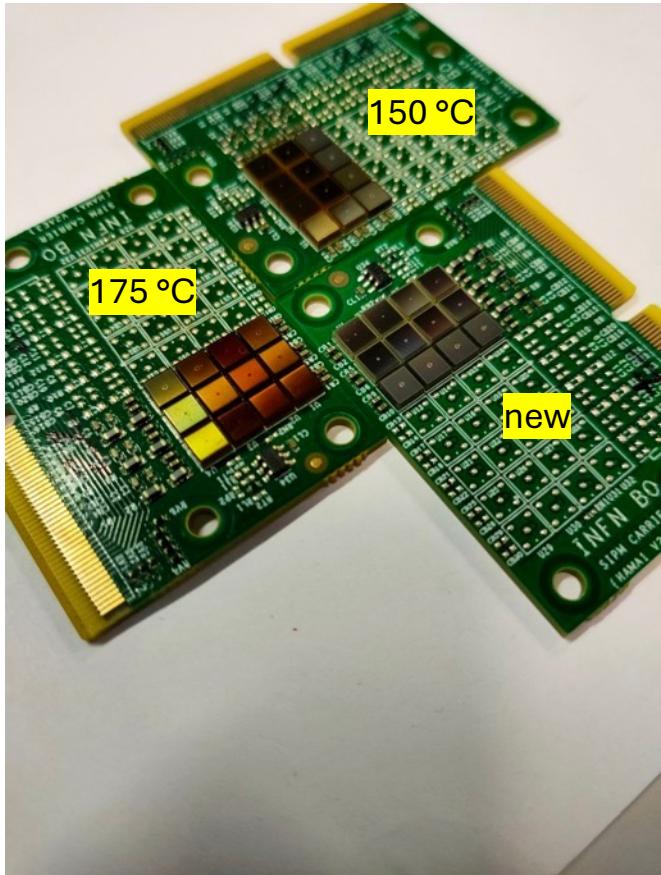
Fraction of damage saturates at 2-3% after 300 h @ 150°C like the oven annealing
 175°C doesn't seem to cure more damage

Update on current annealing

In ocra neutron irradiated boards annealed with single temperature (150-175 °C)



Optical window damage

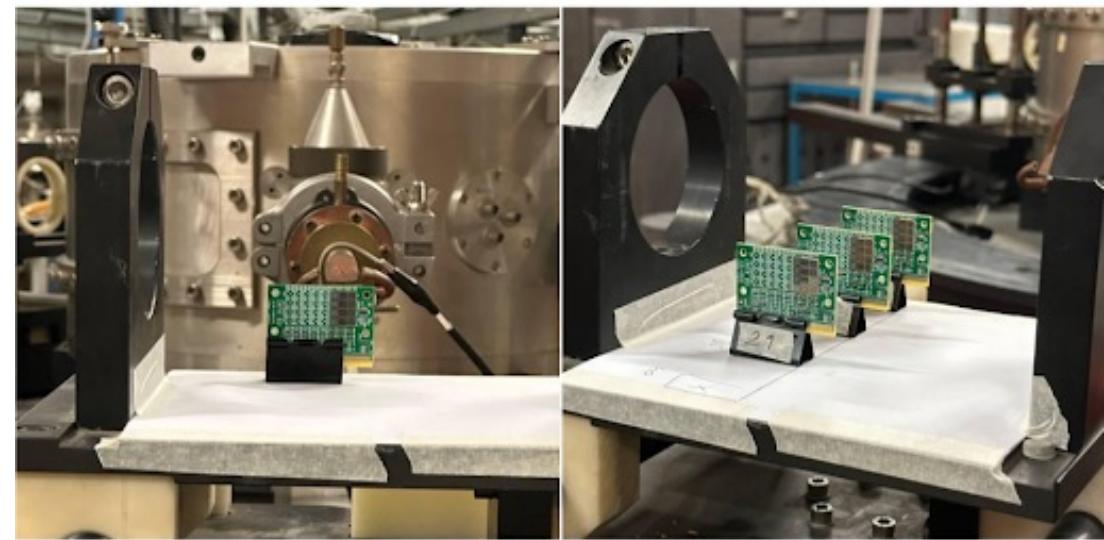
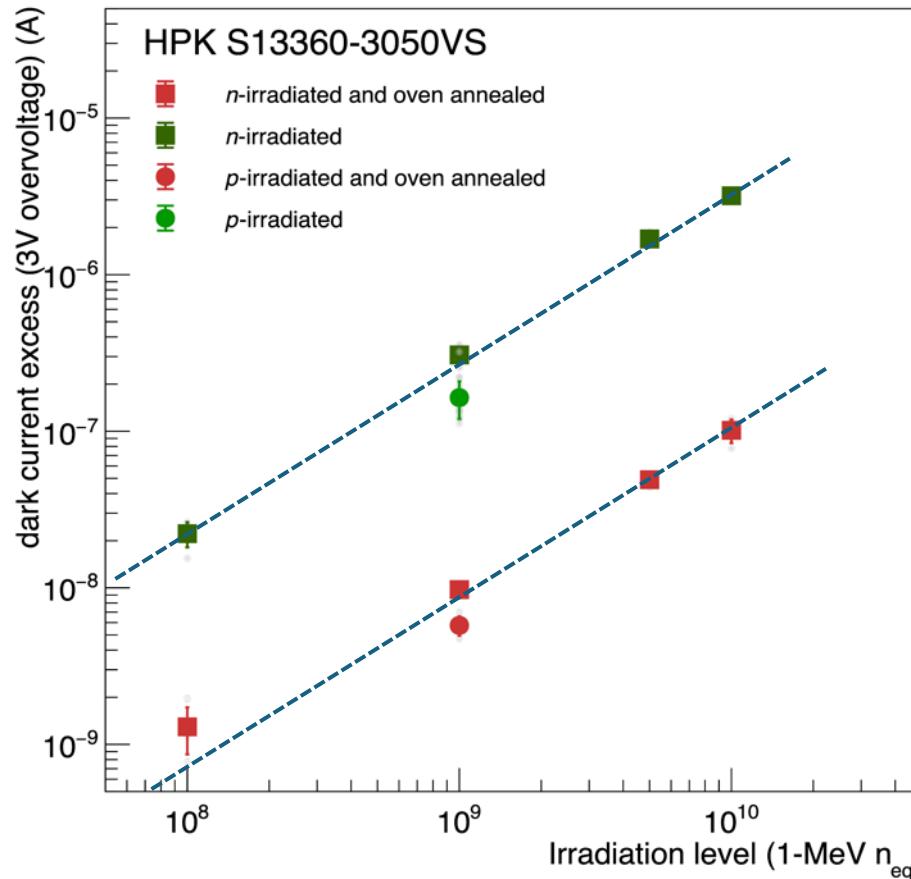


After many hours of online annealing alterations on the SiPM windows
in particular **500 hours** of online annealing at $T = 175\text{ C}$

Neutron irradiation studies

Aug 2023 @ LNL

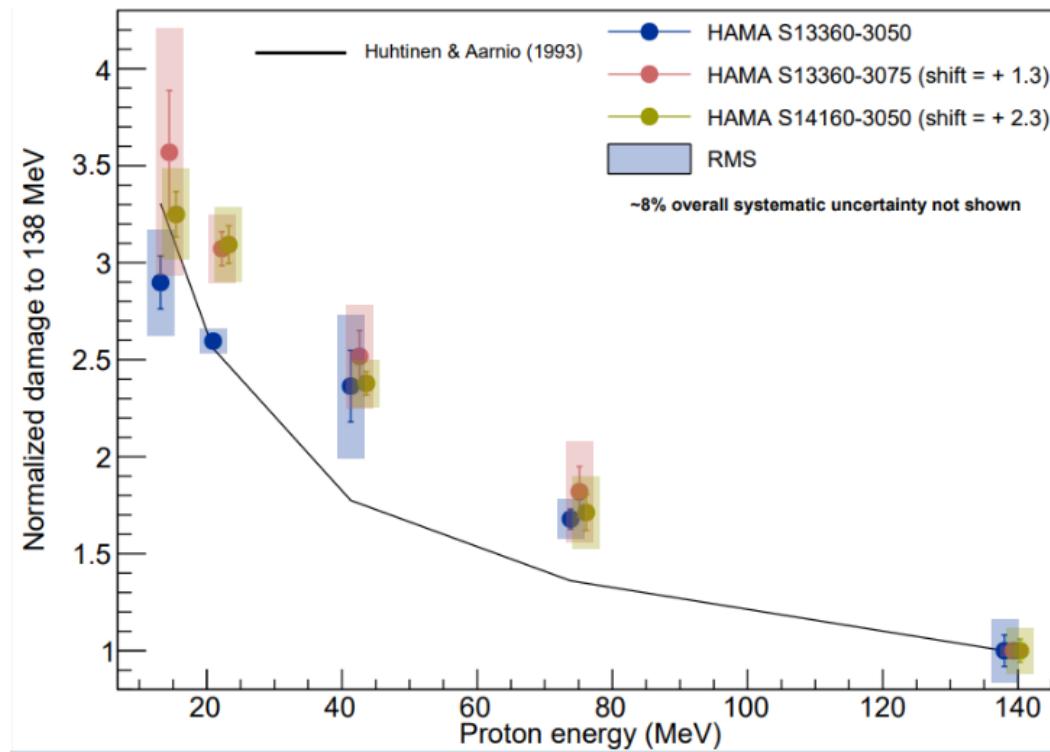
neutrons from Be(d,n) reaction with 4 MeV deuteron beam



Neutron damage is larger after same n_{eq} fluence with protons using **NIEL scaling** for normalisation by approximately a factor of **2x**

NIEL model violation? NIEL is for devices with no gain!

Proton energy scan



Damage vs. proton energy to test NIEL hypothesis

We found that the scaling is valid within 30-50%
using NIEL scaling for normalisation

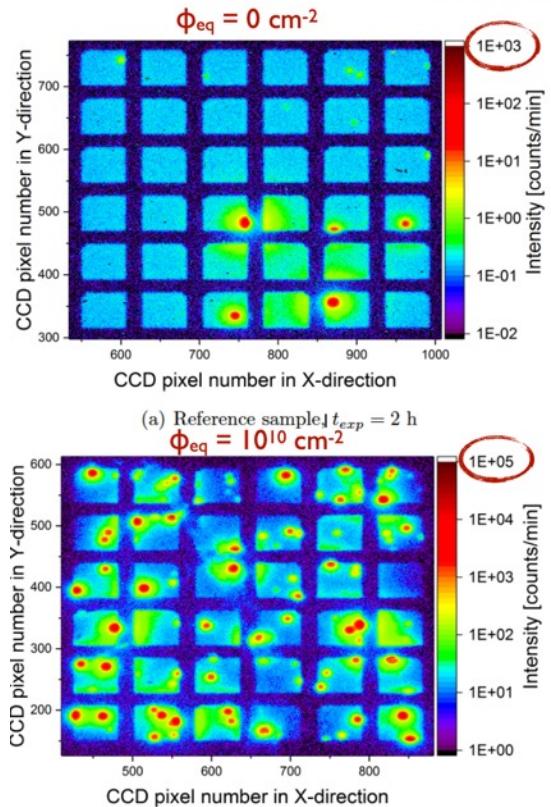
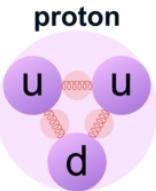
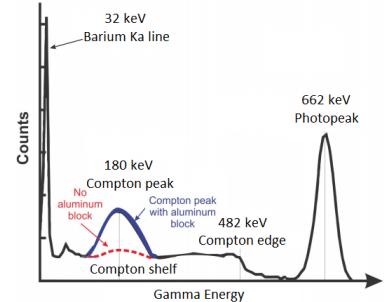
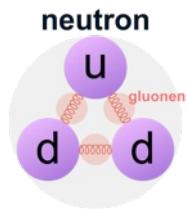
Next irradiation campaigns

Possibility to perform **lock-in thermal imaging (10 mK resolution)** in Dept. of Eng. in **Naples** before and after irradiation

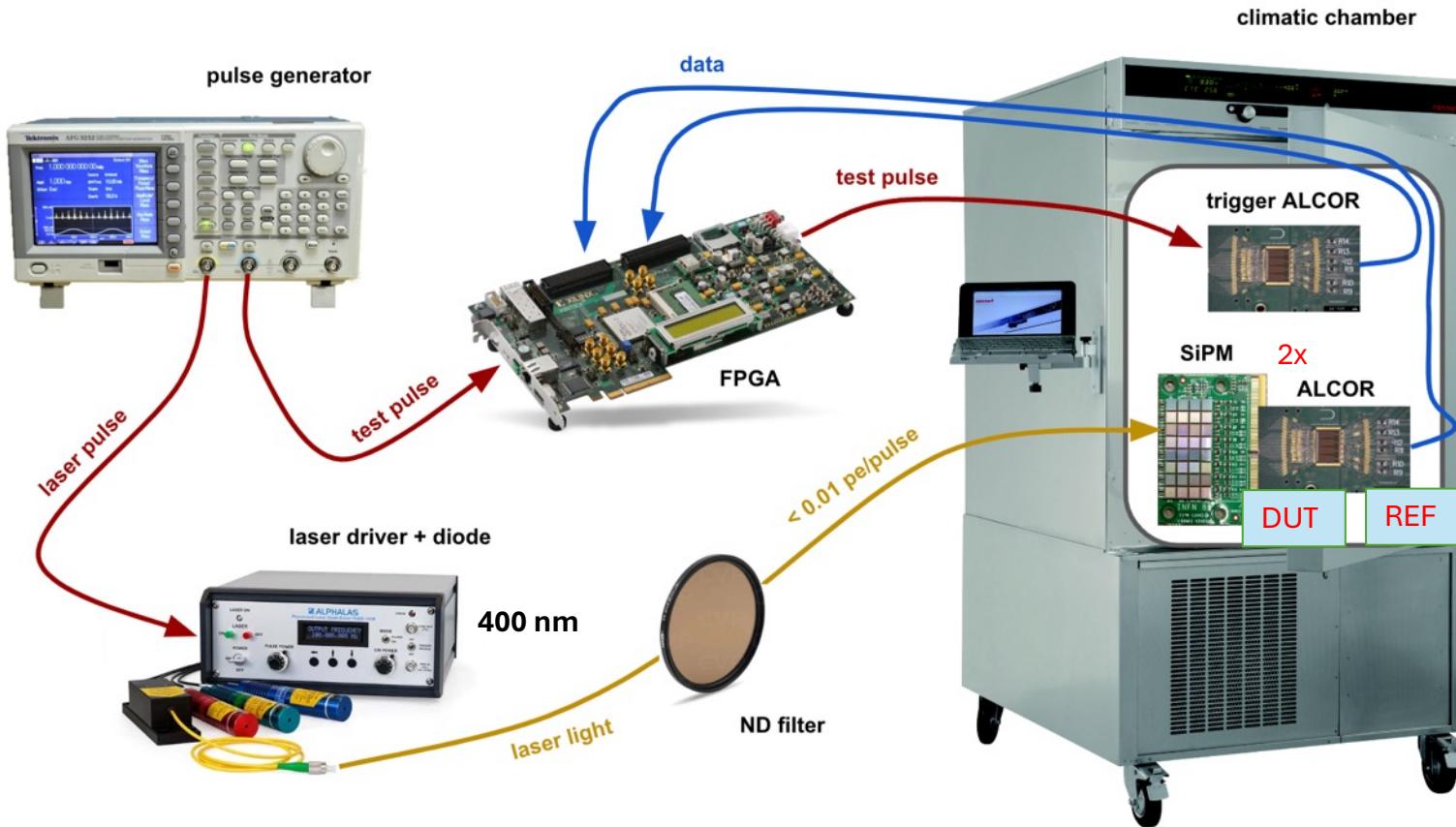
LNL: postponed to second half of **September**

GIF++: 14, 15 ,16 October (first gamma irradiation)

TIFPA: 15-16 Nov and 20-21 Dec (SiPM + electronics)



New laser setup



ALCOR

32-pixel matrix mixed-signal ASIC

- **the chip performs**

- signal amplification
- conditioning and event digitisation

- **each pixel features**

- 2 leading-edge discriminators
- 4 TDCs based on analogue interpolation
 - 25 or 50 ps LSB (@ 320 MHz)
- digital shutter to enable TDC digitisation
 - suppress out-of-gate DCR hits
 - 1-2 ns timing window
 - programmable delay, sub ns accuracy

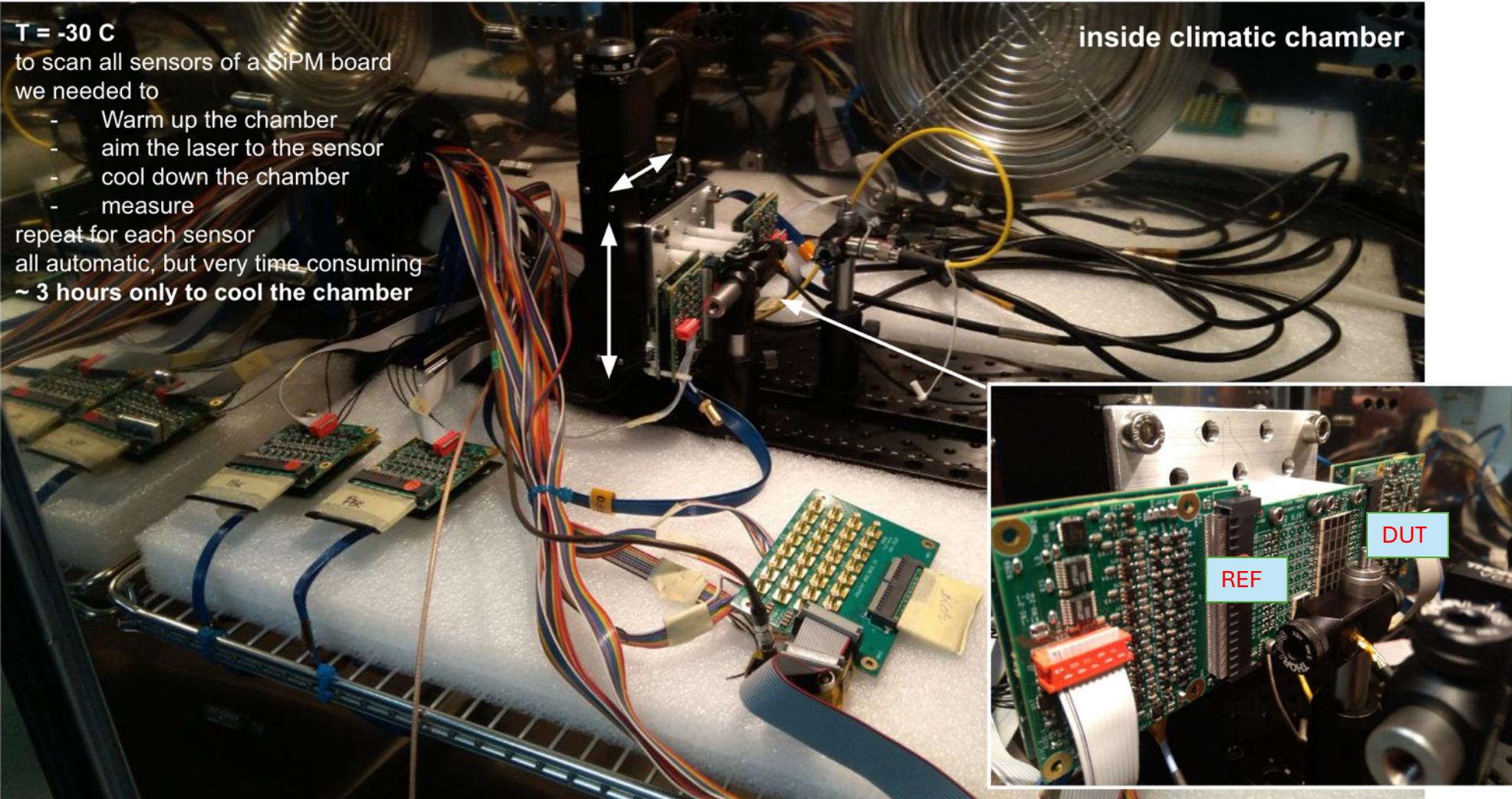
- **single-photon time-tagging mode**

- continuous readout
- also with Time-Over-Threshold

- **fully digital output**

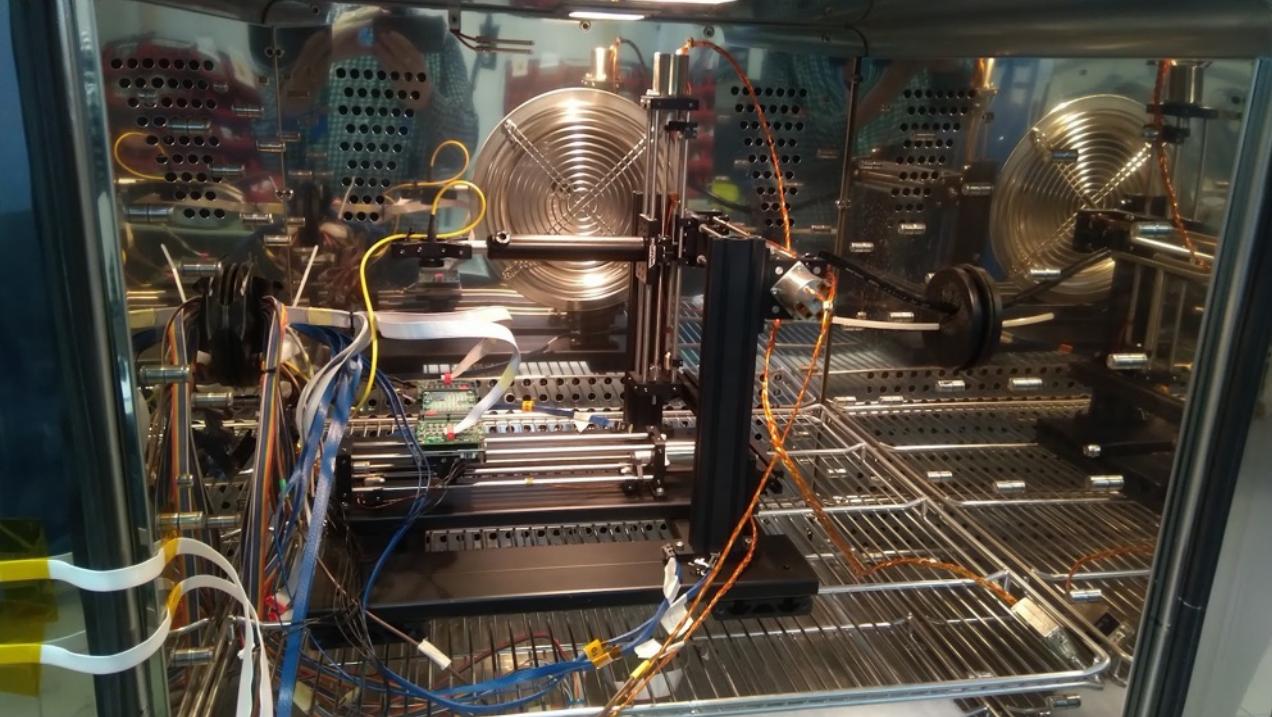
- 4 LVDS TX data links

Old 2 axis stage



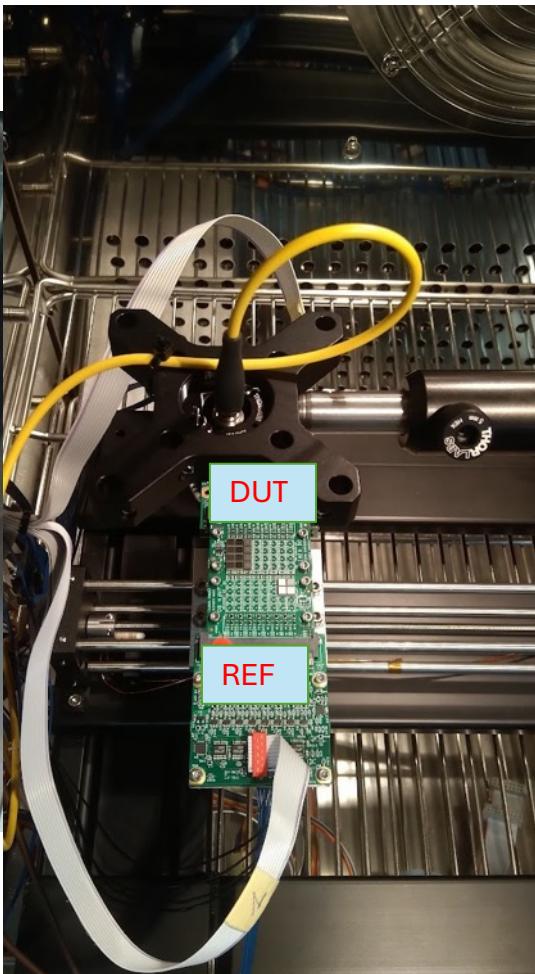
New laser setup 3 axis stage

$\lambda=400 \text{ nm}$ 1 mm² single photon spot



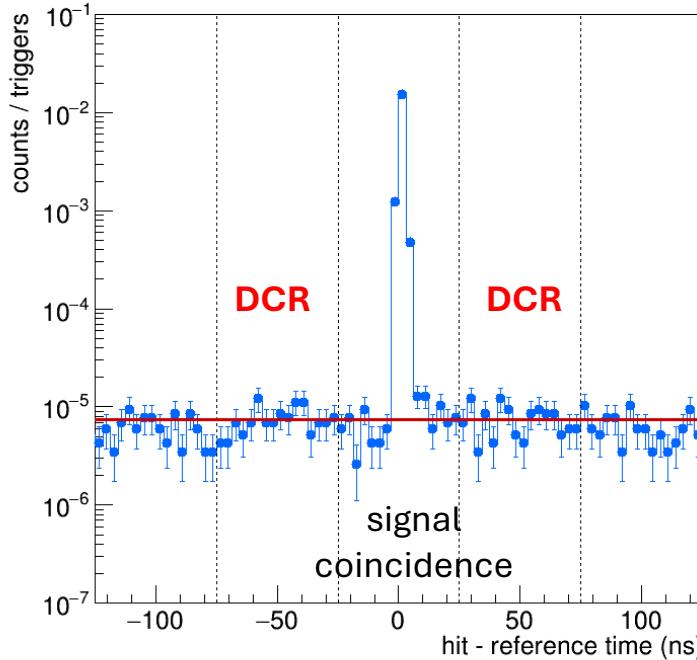
working down to -40 °C

Allow to measure a DUT and the reference sensor without thermal cycling the system

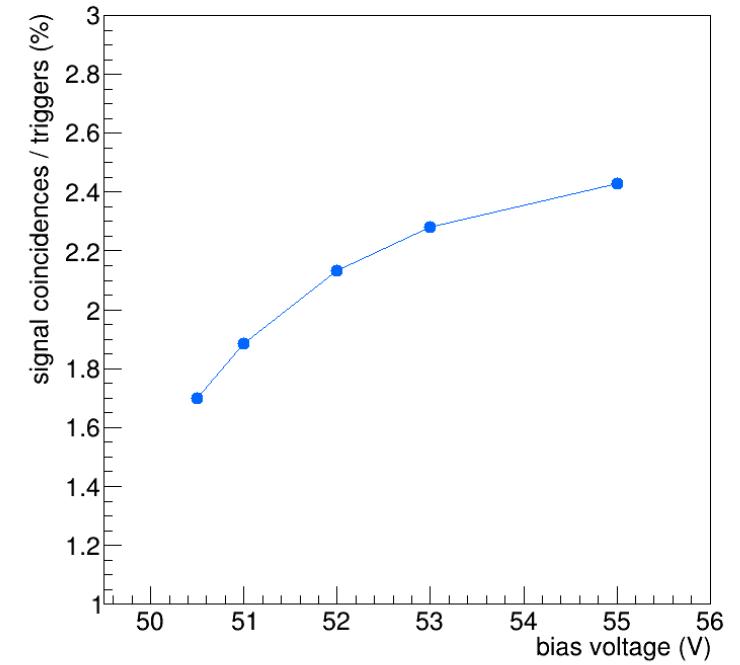
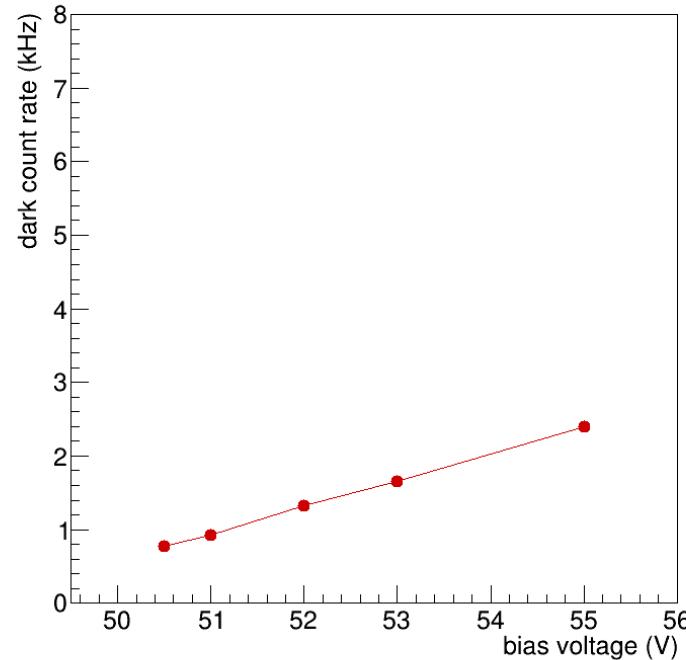


New laser setup measurements example

measured signal coincidences



background-subtracted counts / triggers



probability to detect light given laser pulse \propto PDE

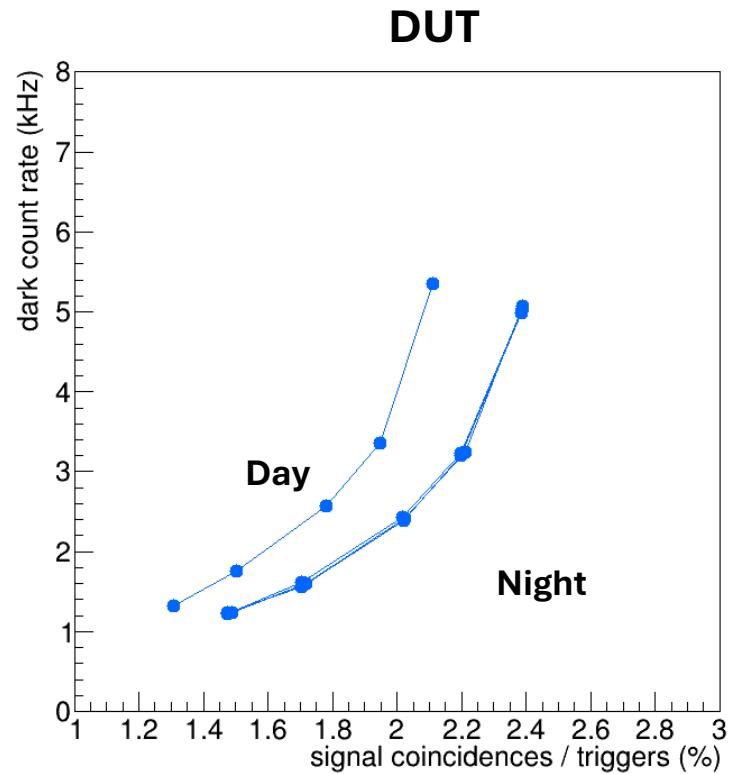
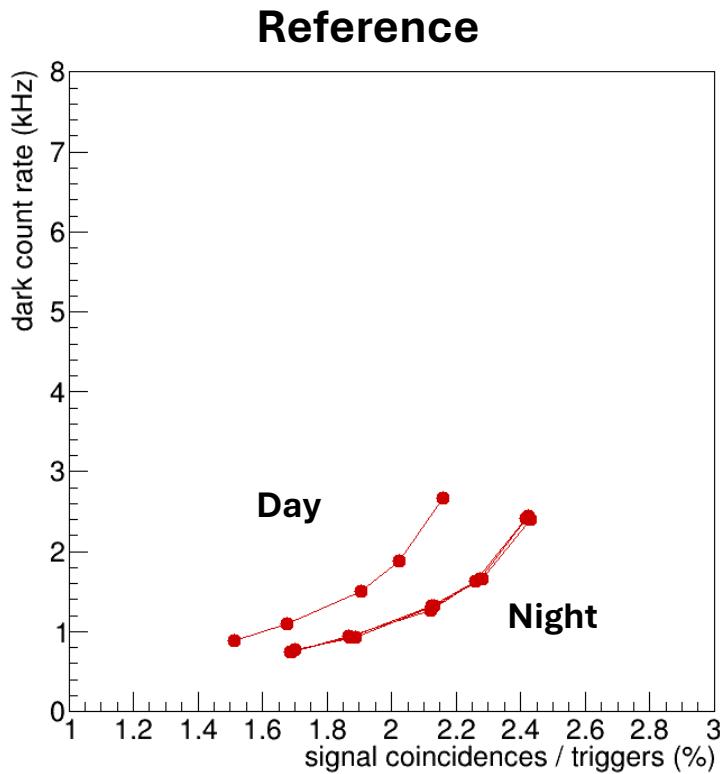
Reference-DUT

Is it really needed?

Reference-DUT

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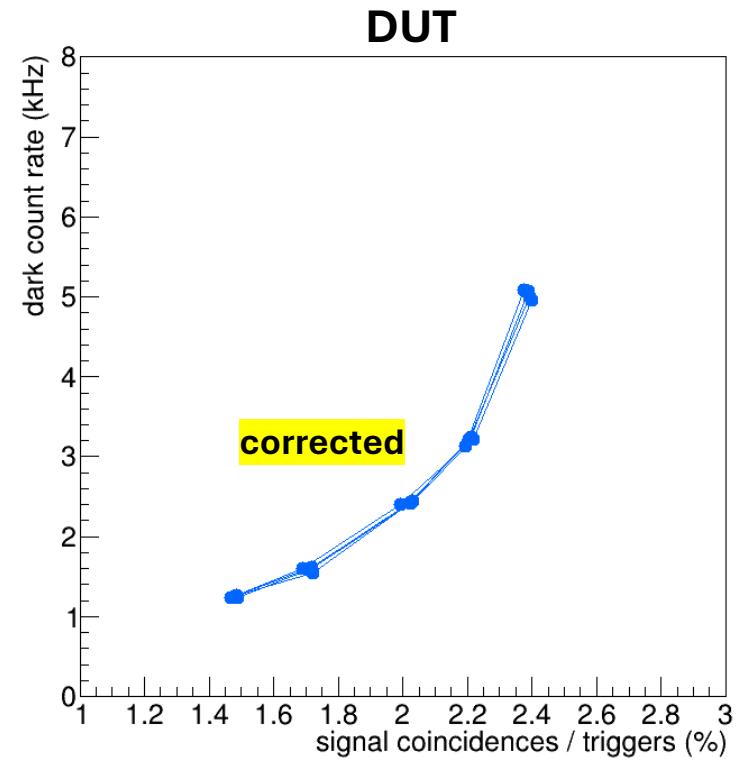
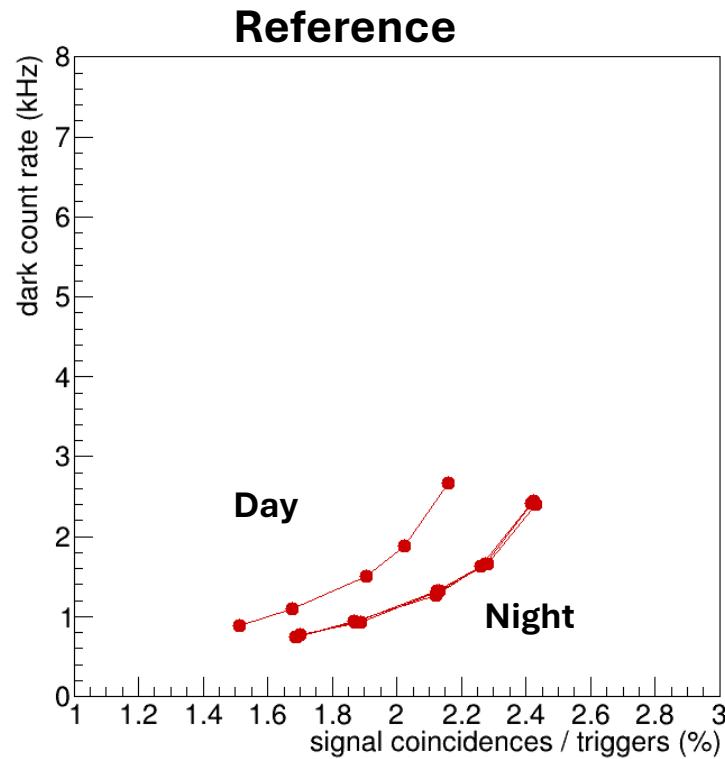
Yes



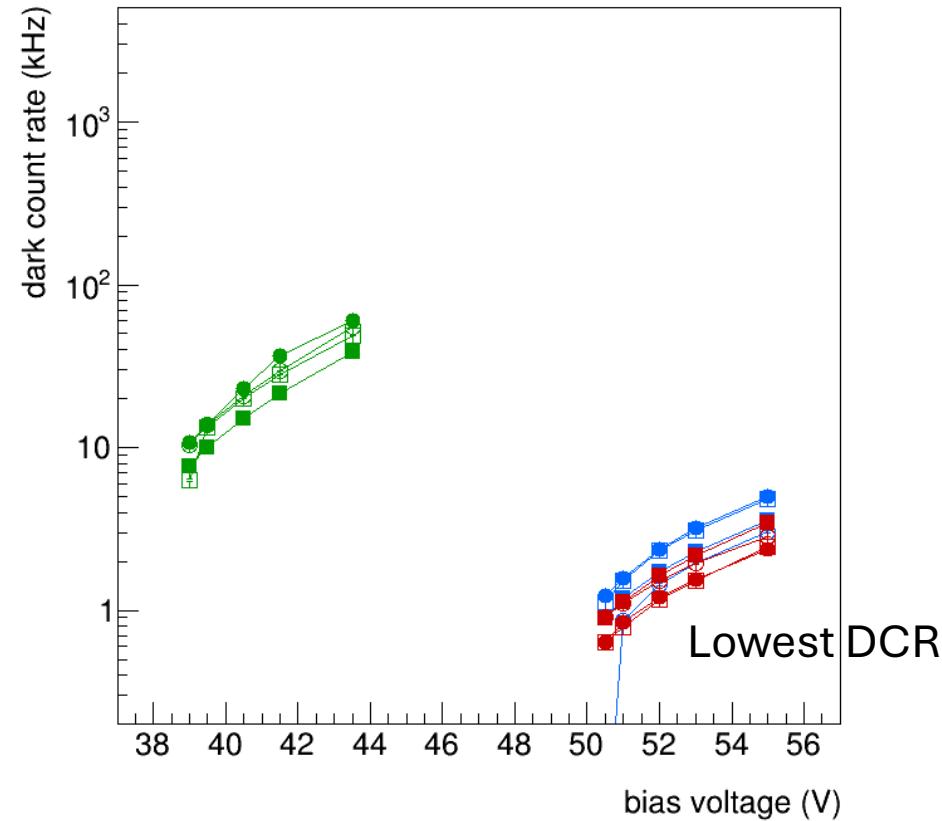
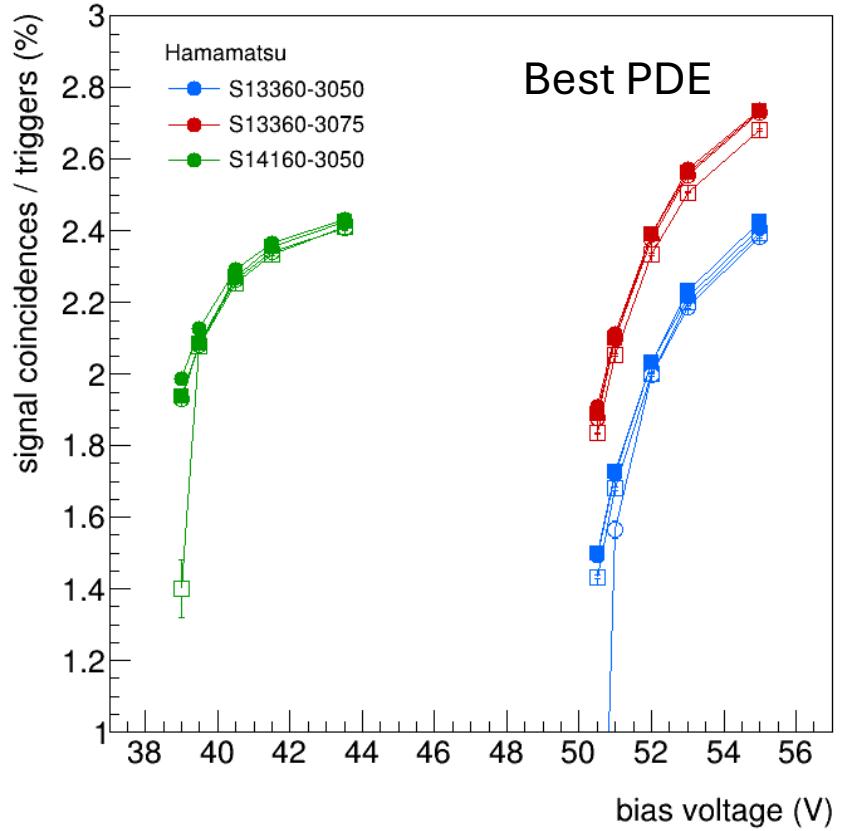
Reference-DUT

Is it really needed?

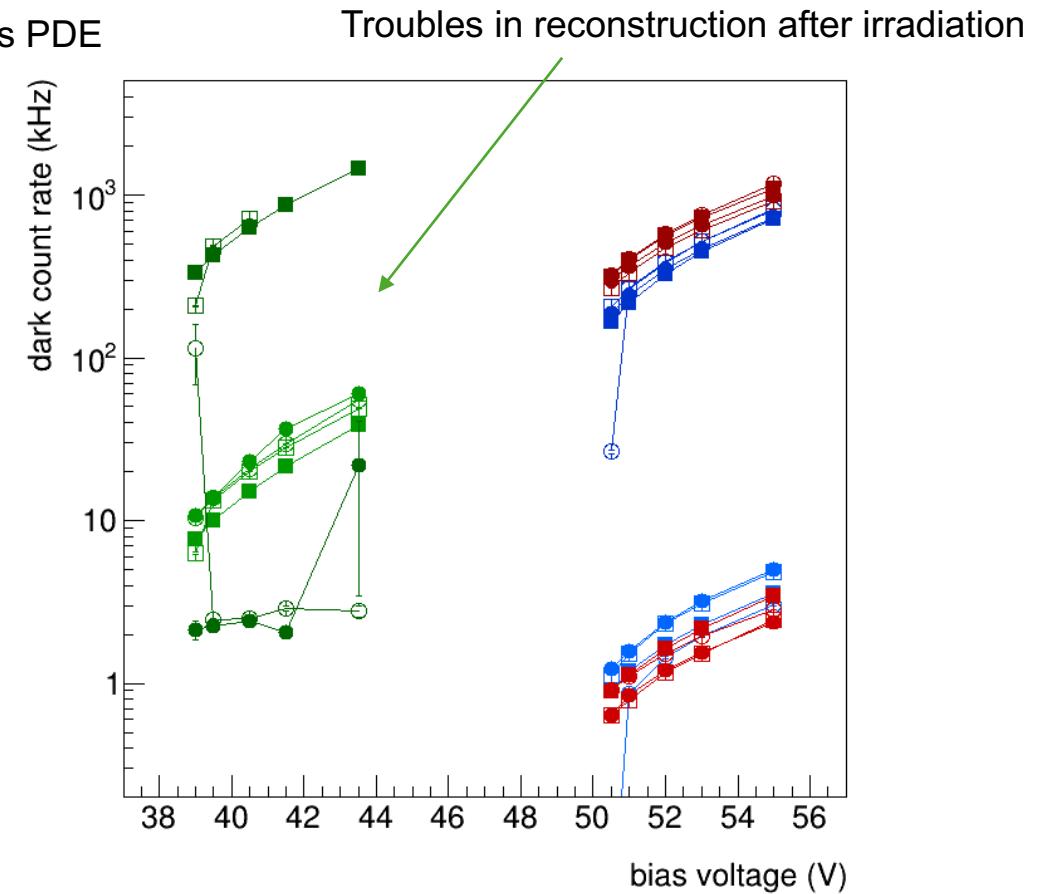
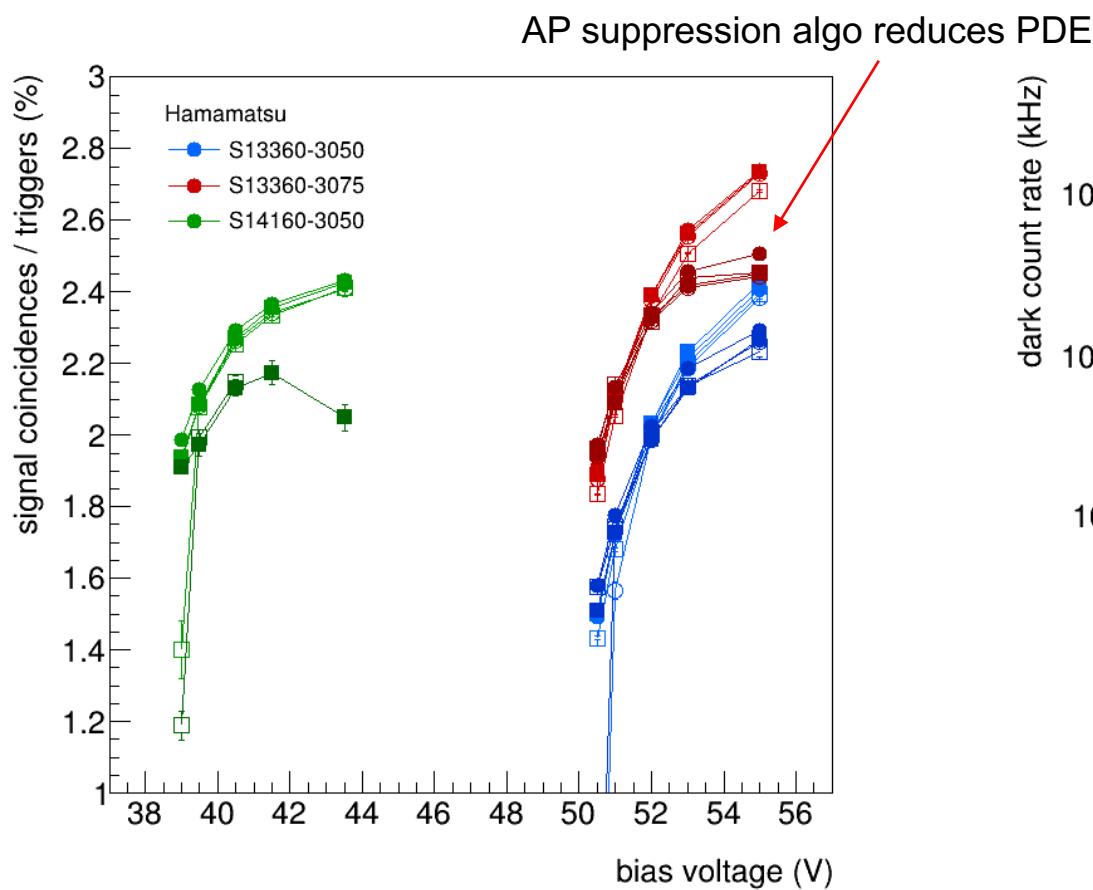
Yes



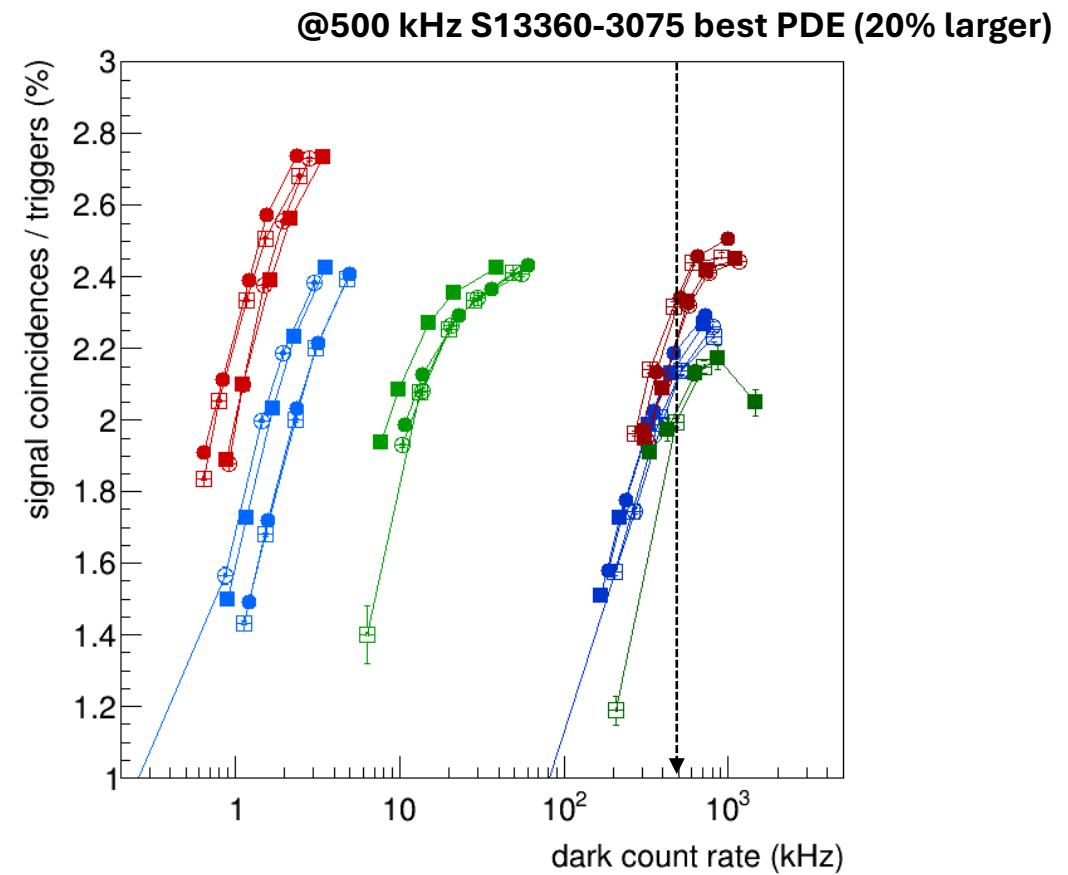
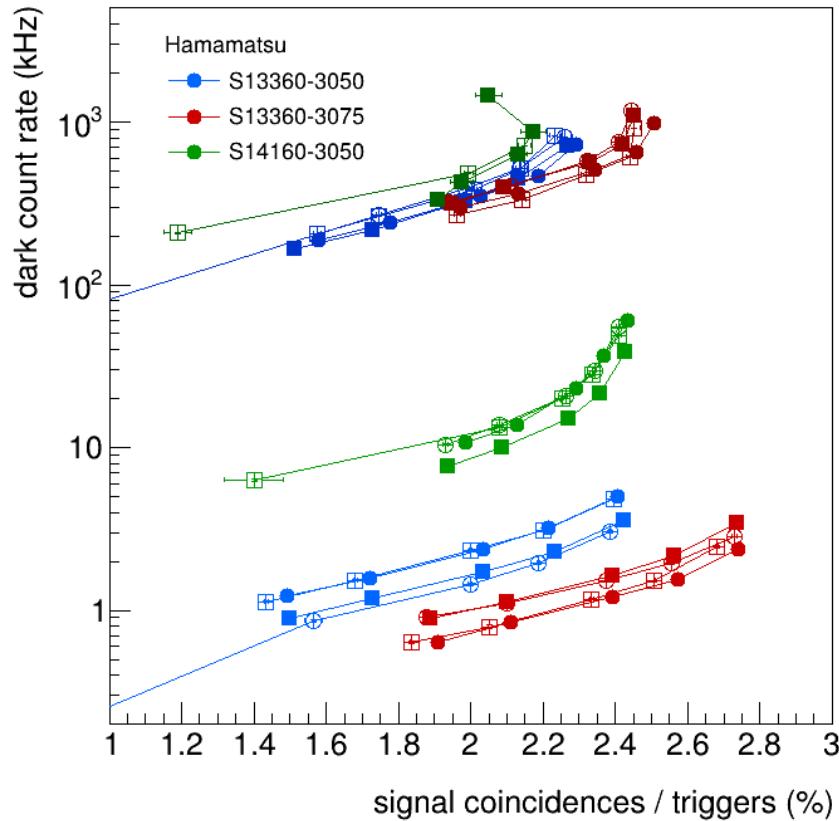
Pseudo efficiency: new boards



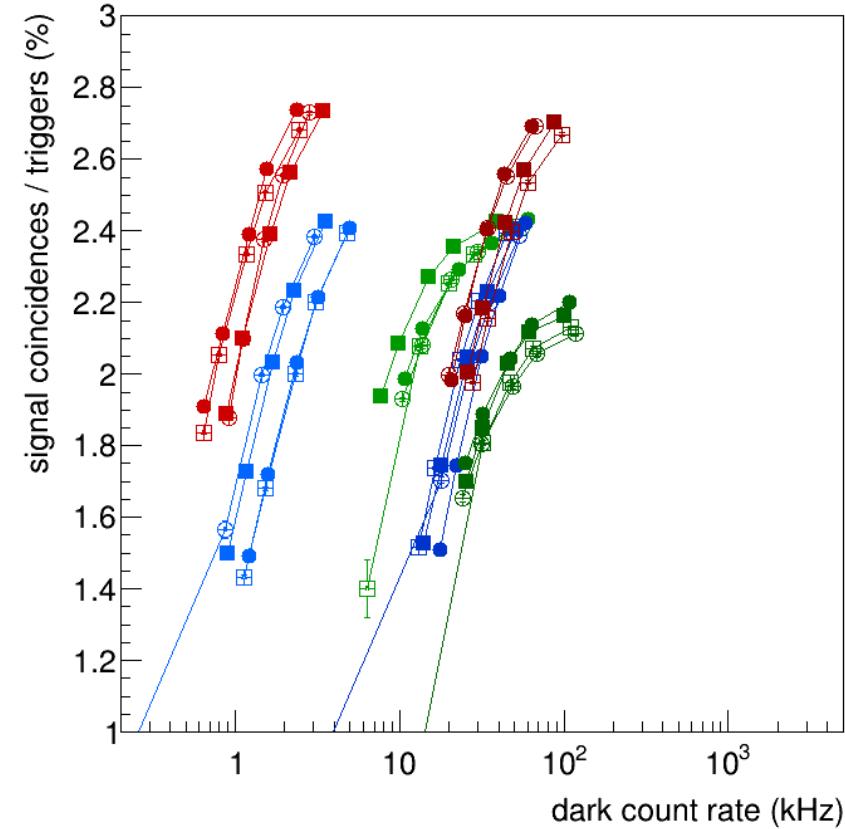
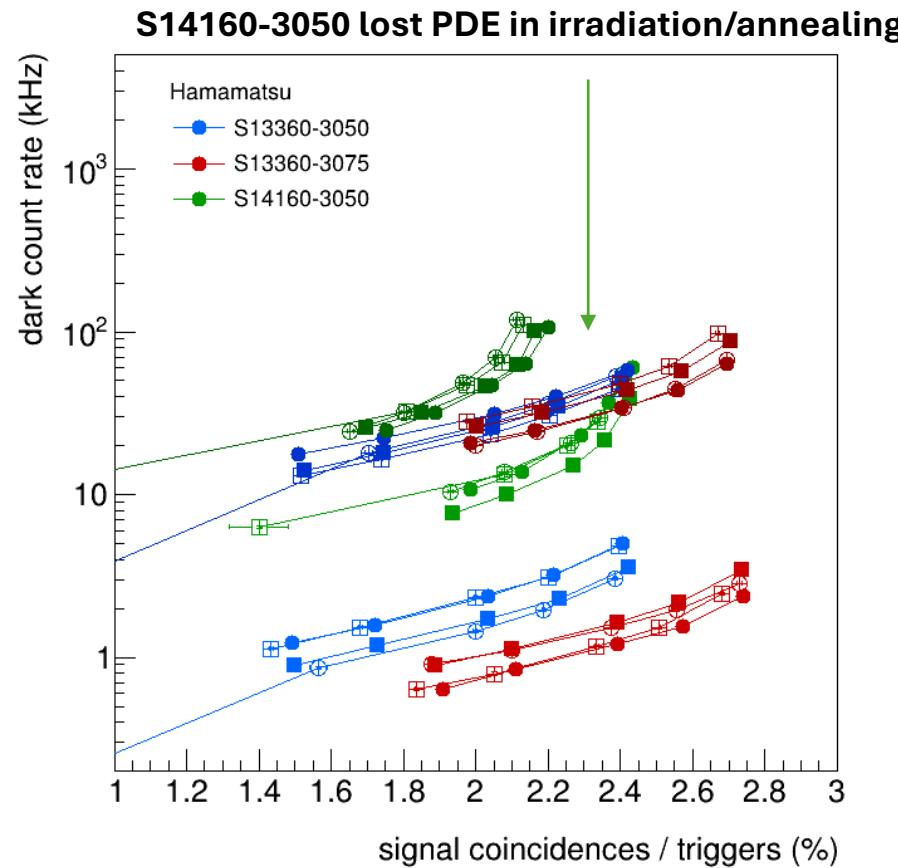
Pseudo efficiency: new and 10^9 n_{eq}



Pseudo efficiency: new and $10^9 n_{eq}$ better view

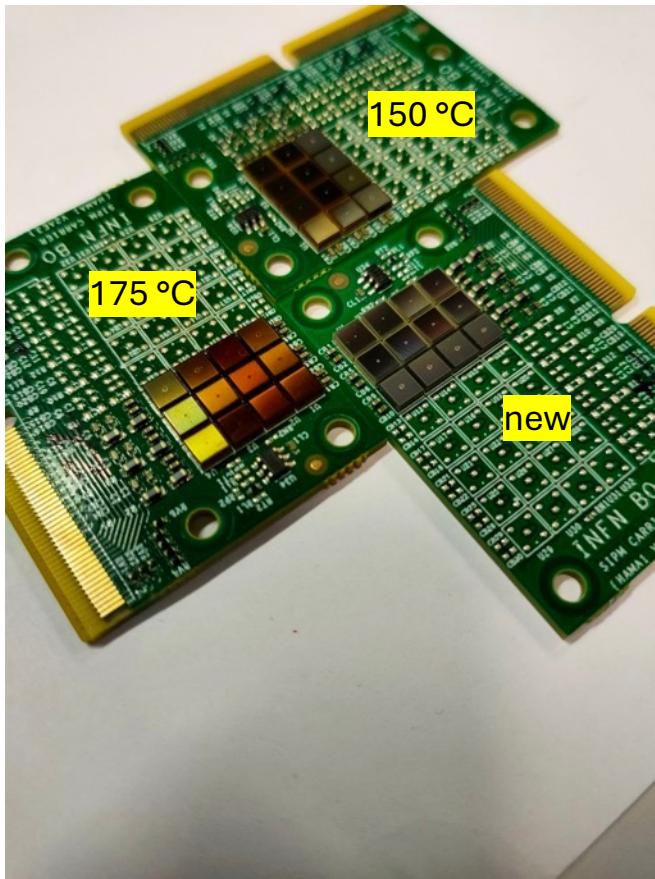


Pseudo efficiency: new and annealed

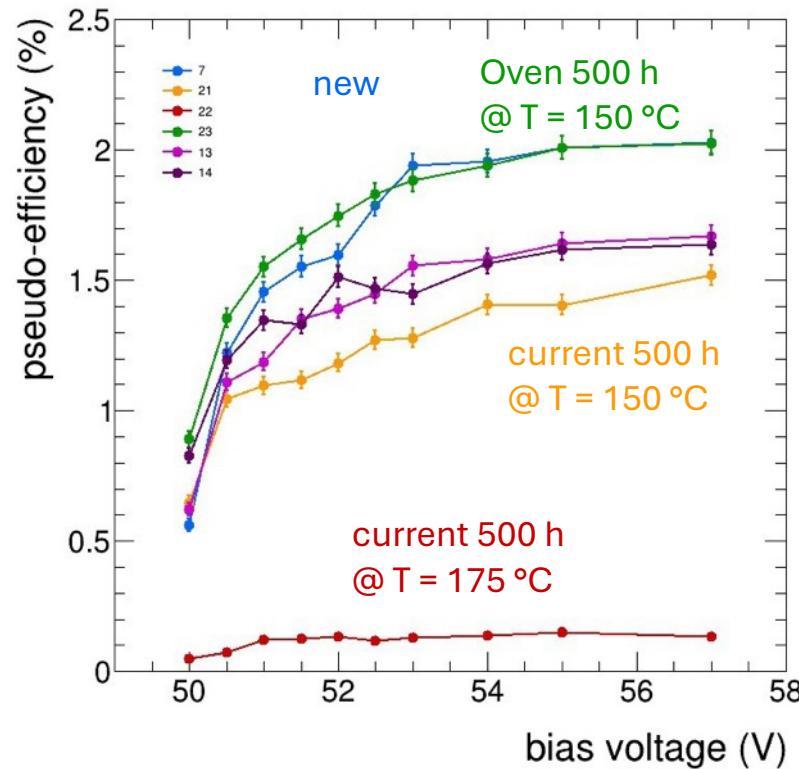


S13360-30xx no PDE loss, only increase in DCR

Windows damage studies



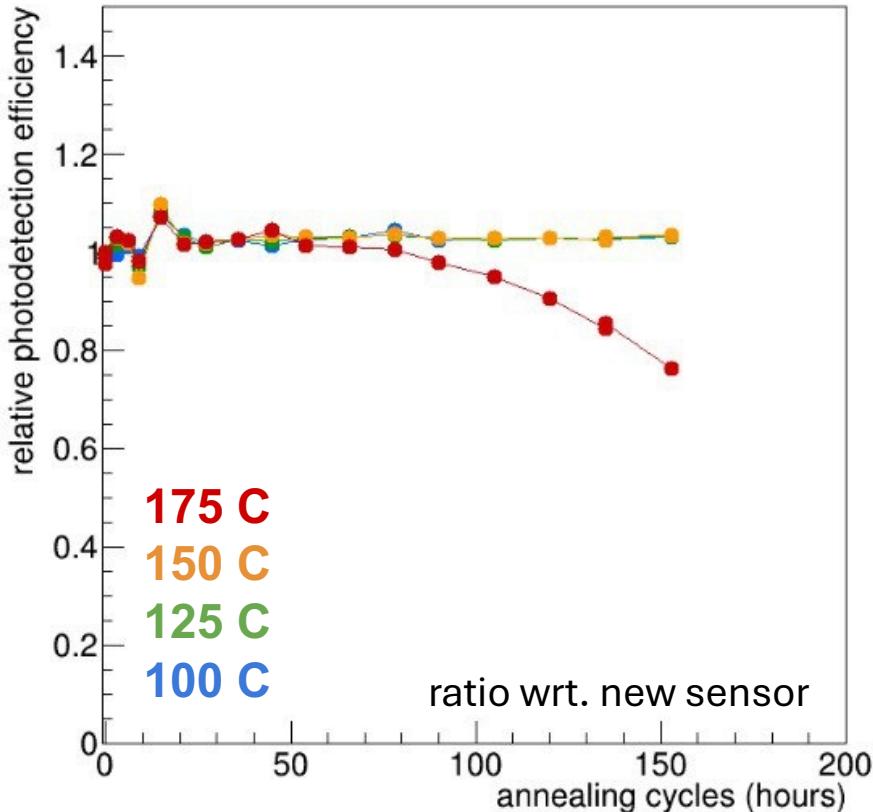
After many hours of online annealing alterations on the SiPM windows
in particular 500 hours of online annealing at $T = 175\text{ C}$



- 90% efficiency loss after 500 h online at 175 C
- 25% efficiency loss after 500 h online at 150 C
- no efficiency loss after 500 h oven at 150 C

Unclear why oven annealing is less critical on window

Windows damage further studies



4 SiPMs under study at forward bias and different temperatures.

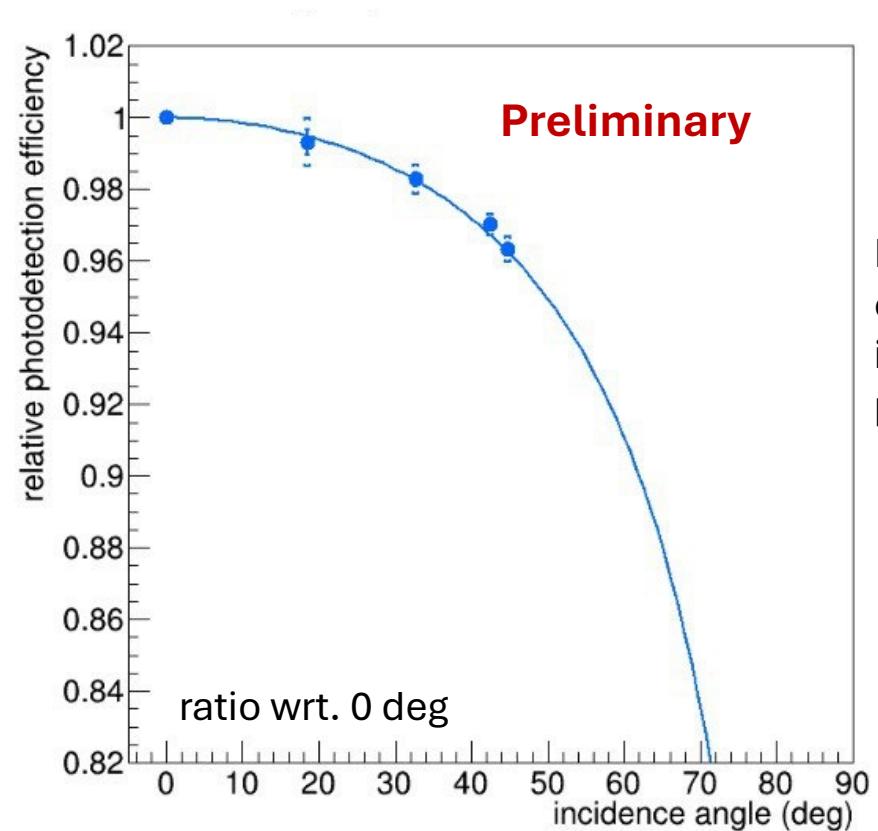
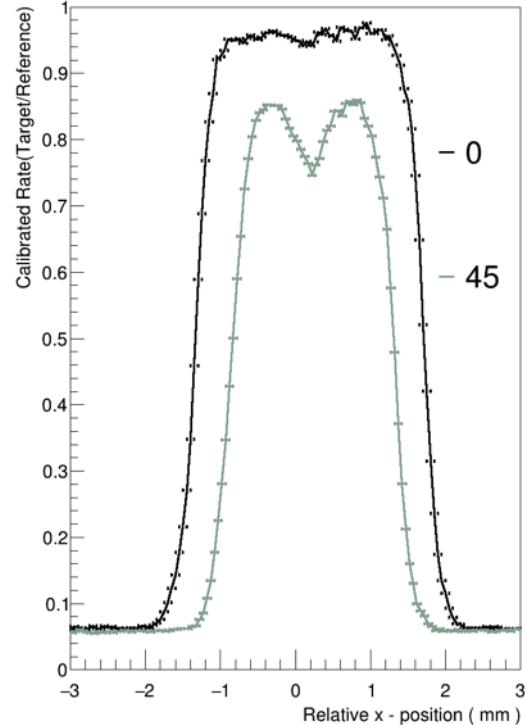
After 50 h @175 C the PDE starts to drop

After 150 h @150 C the PDE is still ok

The point before the last one was taken after 20 days and the results are the same (20 days no annealing)

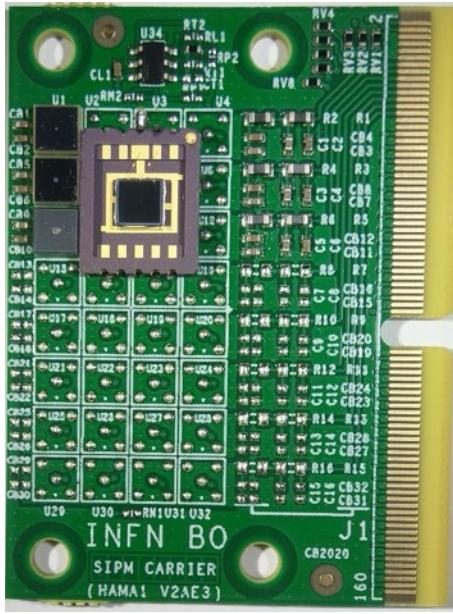


Pseudo-efficiency vs incident angle

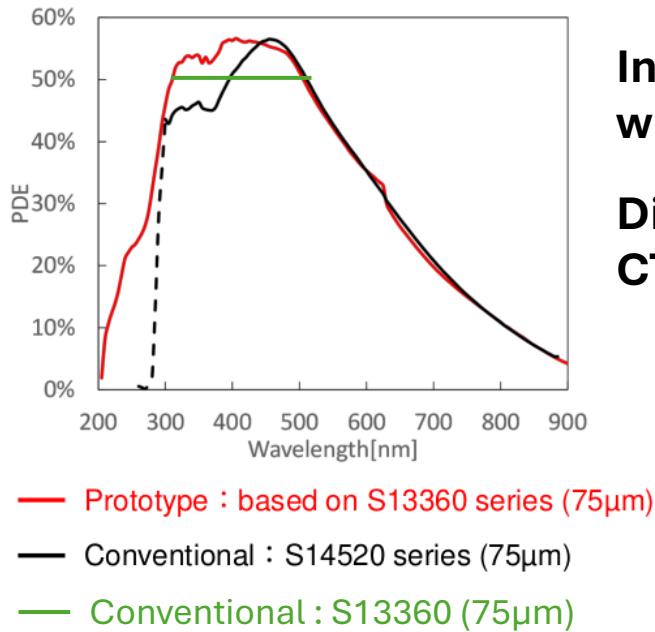


Measurement is still ongoing. Up to now the loss in efficiency doesn't seem problematic

New Hamamatsu prototype



Prototype S13360-3075-UVE

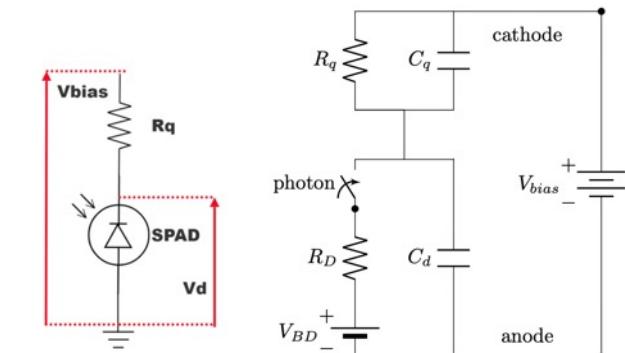
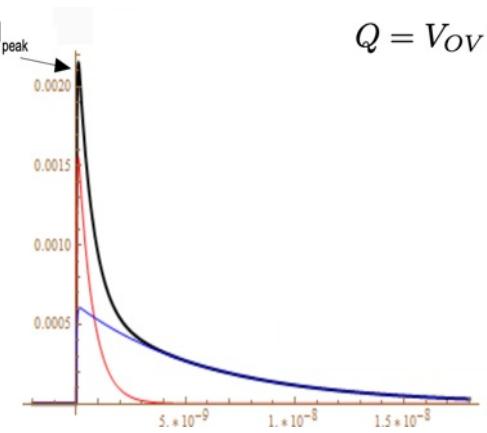


Increased PDE in the blue region thanks to quartz window and different passivation

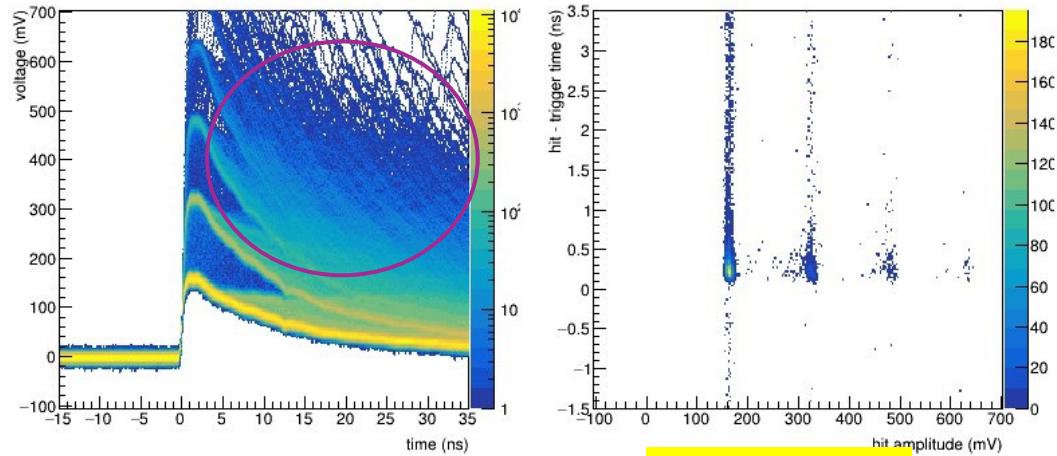
Different quenching resistor: faster signal, less AP and CT

$$I(t) \simeq \frac{Q}{C_q + C_D} \left(\frac{C_q}{\tau_{fast}} e^{\frac{-t}{\tau_{fast}}} + \frac{C_D}{\tau_{slow}} e^{\frac{-t}{\tau_{slow}}} \right)$$

$$Q = V_{OV}(C_D + C_q)$$

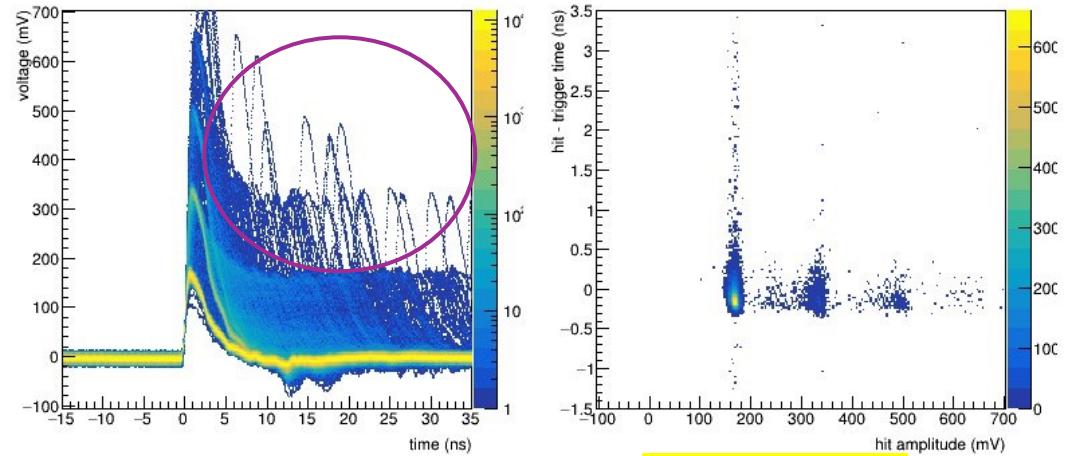


Conventional S13360-3075-VS

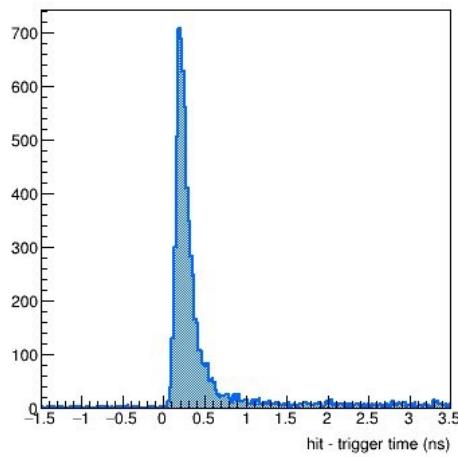


Same amplitude

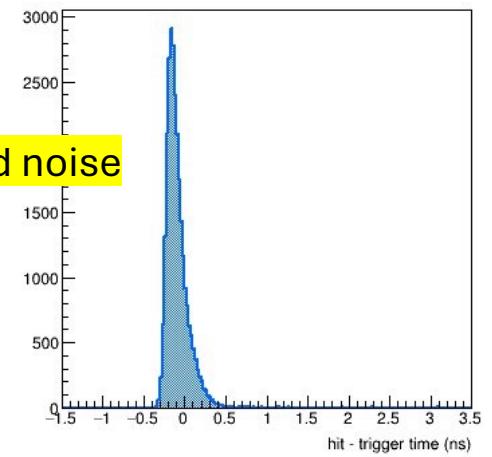
Prototype S13360-3075-UVE

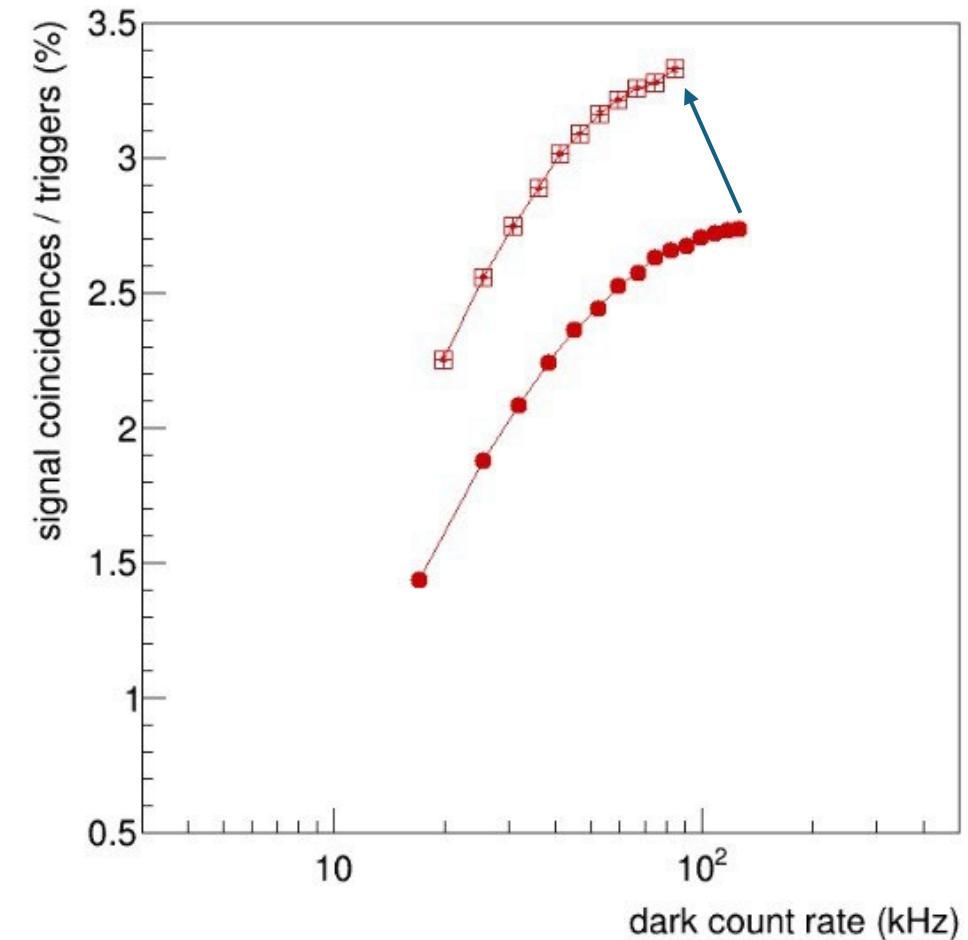
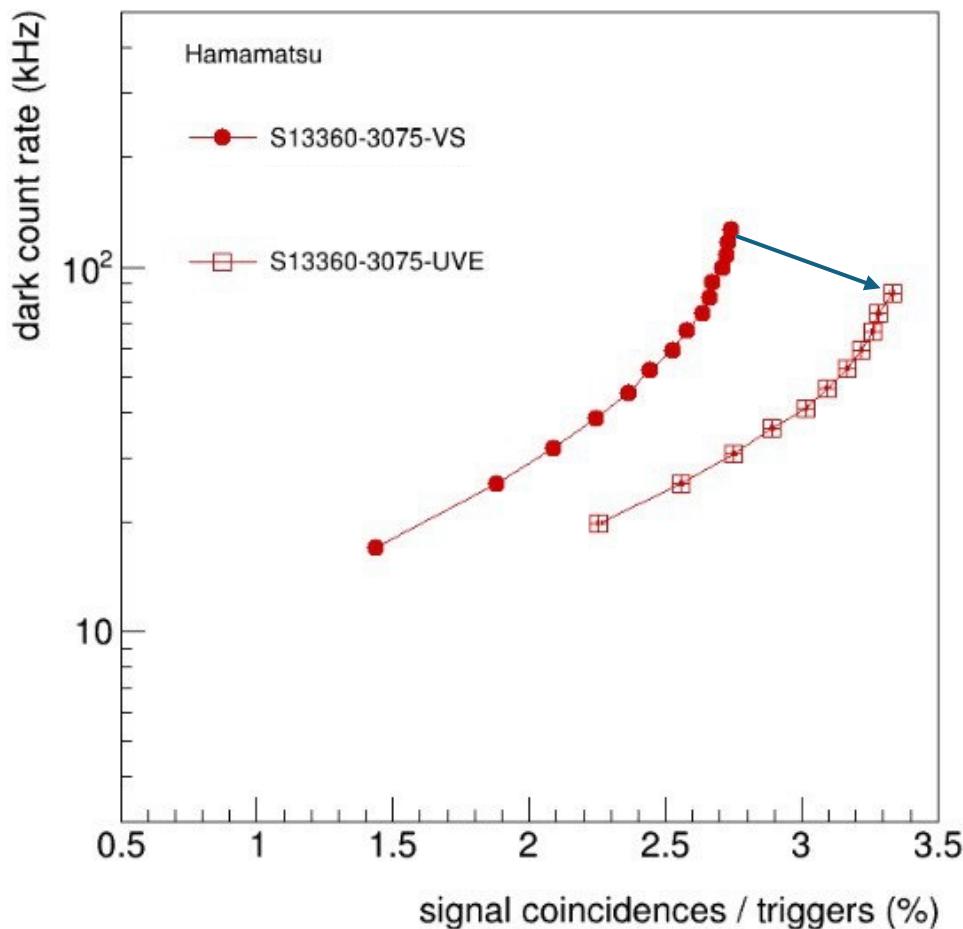


Same amplitude

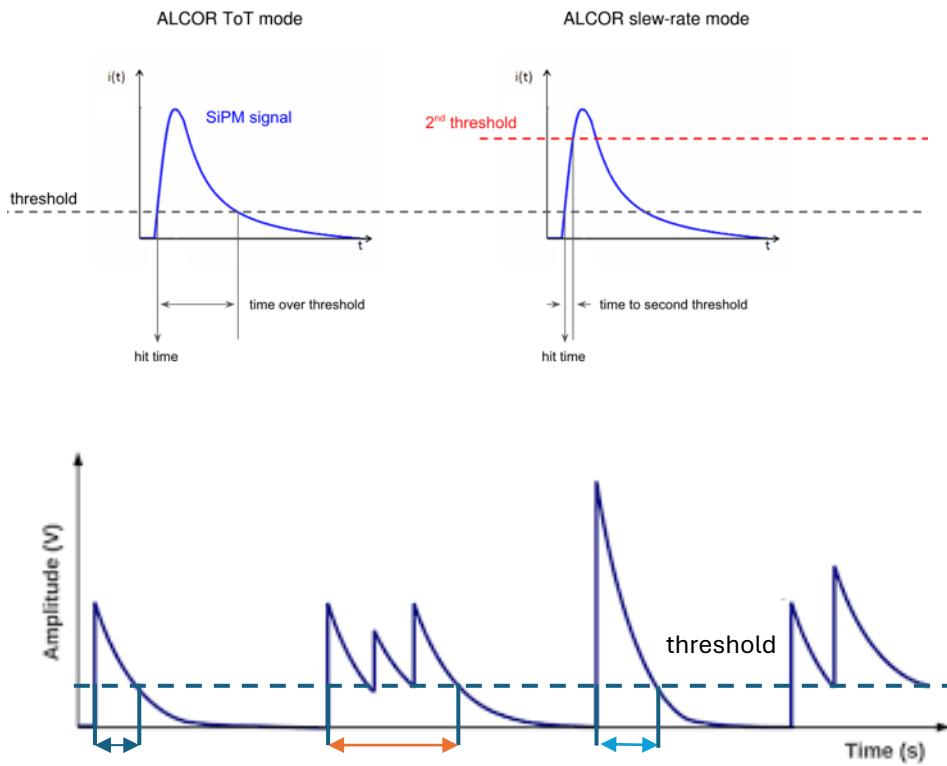


Faster
Less correlated noise



**Increase PDE
With lower DCR****Increase PDE
With lower DCR**

Alcor ToT vs Slew rate mode

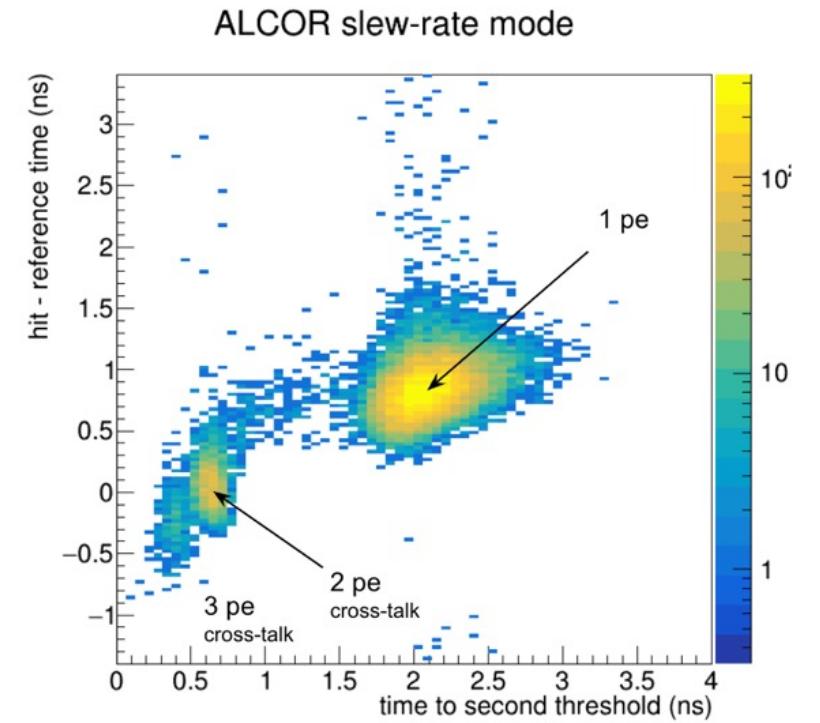
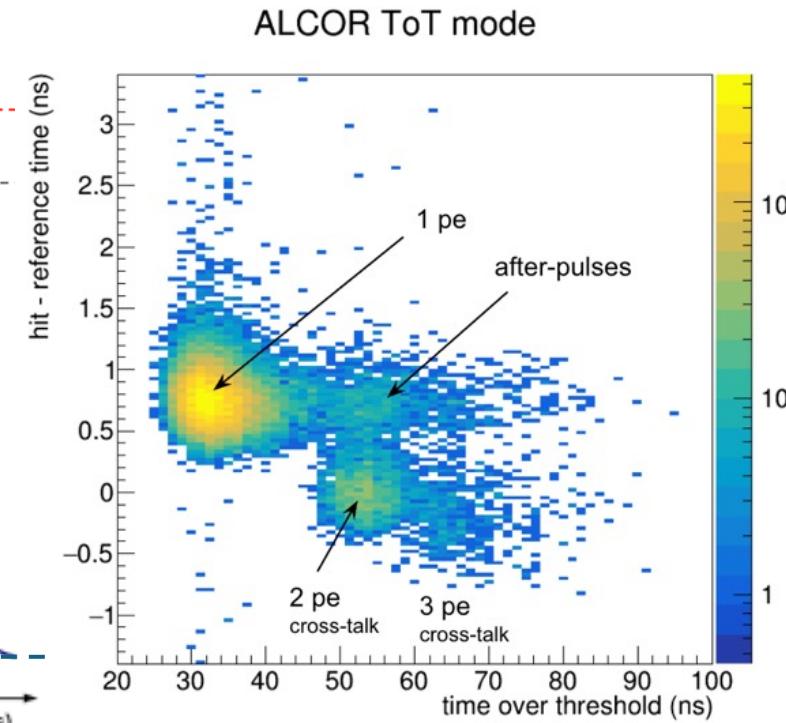
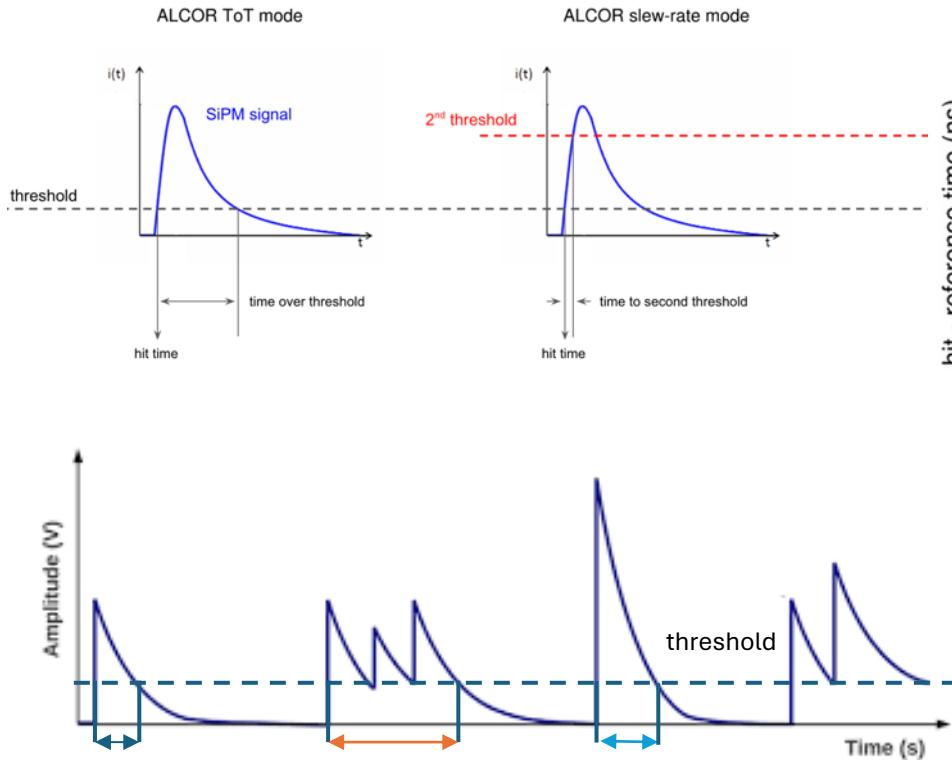


Hit time defined by when the signal goes over a fixed threshold.

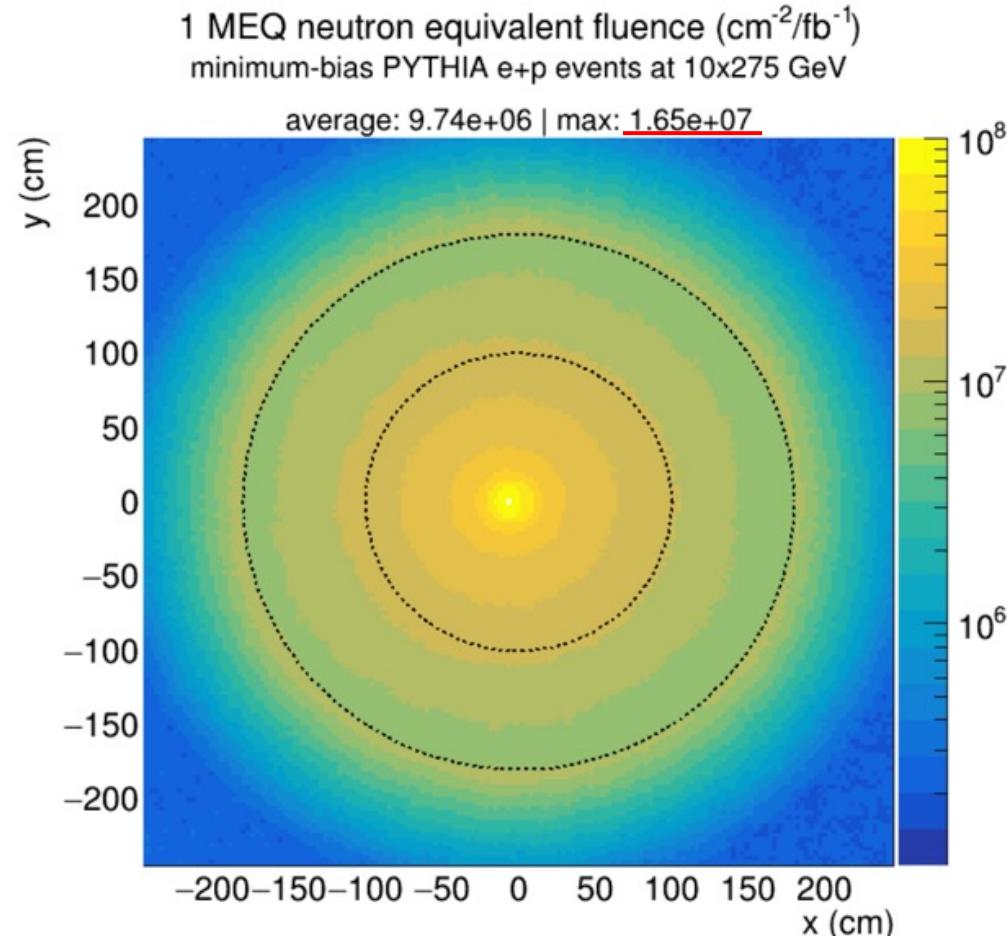
Time walk correction is needed: bigger signals arrive in advance.

ToT is proportional to the number of detected PEs (signal amplitude) but what if afterpulses?

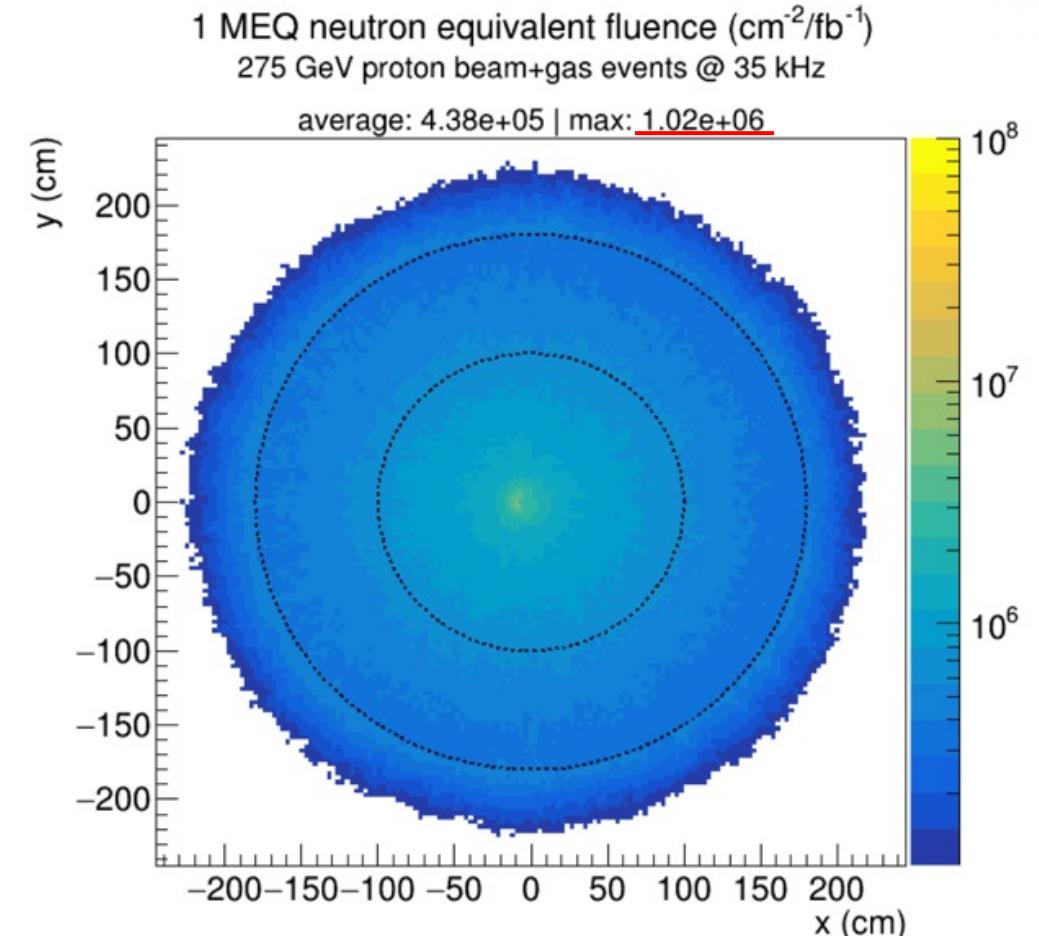
Alcor ToT vs Slew rate mode



New dose estimates



Last year estimation with a safety factor x2
Max fluence $\approx 4.5 \text{ } 10^7 \text{ n}_{\text{eq}}/\text{cm}^2/\text{fb}^{-1}$



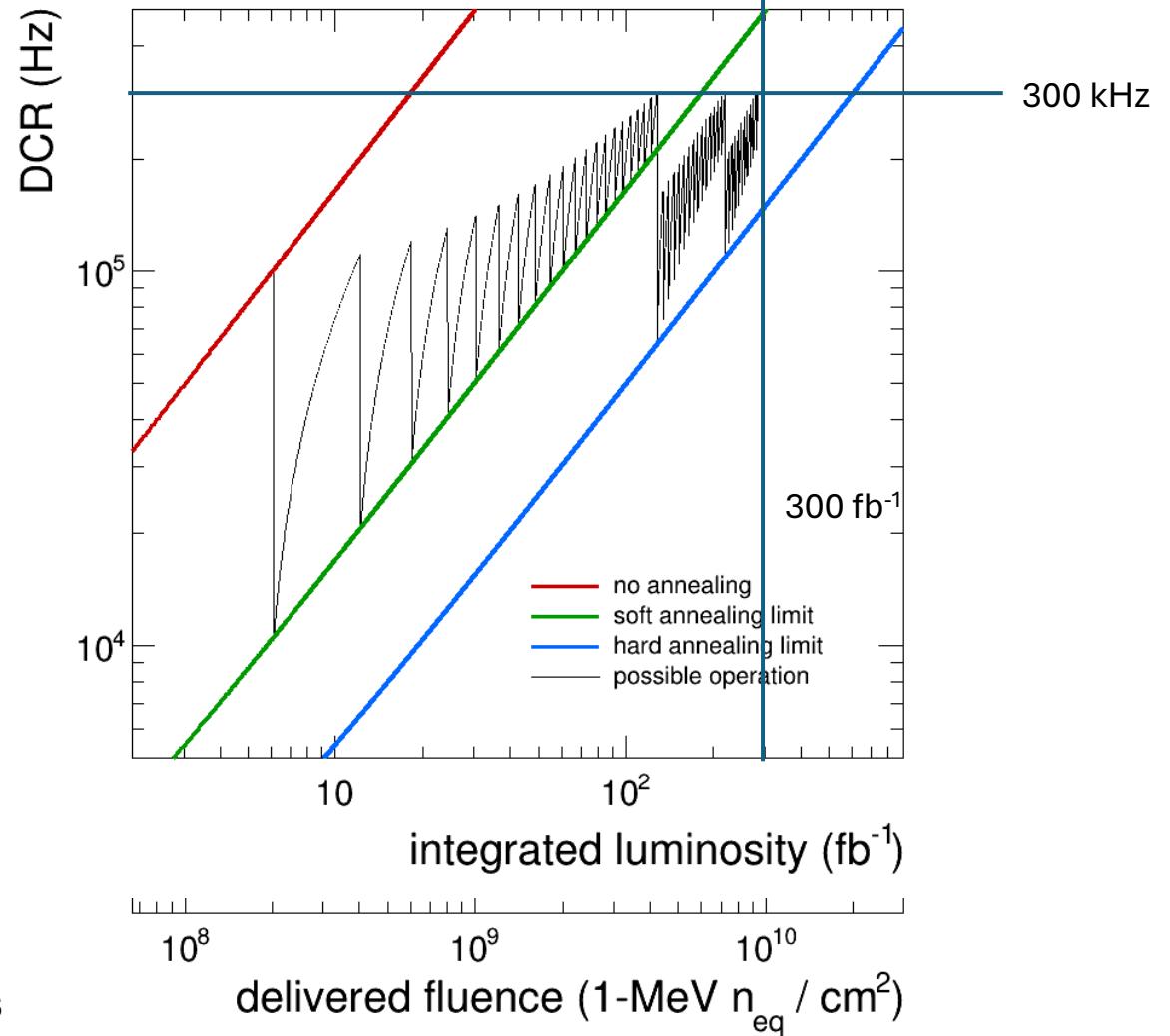
Latest simulations give us
Max fluence $\approx 1.75 \text{ } 10^7 \text{ n}_{\text{eq}}/\text{cm}^2/\text{fb}^{-1}$

New ageing model

Model assumption:

- DCR increase: $500 \text{ kHz}/10^9 n_{\text{eq}}$
- residual DCR (soft 2 h@150C annealing): $50 \text{ kHz}/10^9 n_{\text{eq}}$
- residual DCR (hard 100 h@150C annealing): $15 \text{ kHz}/10^9 n_{\text{eq}}$
- **1-MeV neq fluence from background group**
 - $1.75 \cdot 10^7 n_{\text{eq}} / \text{fb}^{-1}$
 - Add 2x safety factor

Hamamatsu S13360-3050 @ Vover = 4 V, T = -30 C



Proposed operation scenario:

44 soft-annealing cycles and 3 hard-annealing cycles